

# RUTRONIK TechTalk meets **Gate Driver**

## Fast switching SMPS Gate Drivers

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Infineon Technologies AG

“Every switch needs a driver !”

High efficiency, high power density and the aim for cost efficient design are today's application requirements.

These are in turn requiring **fast switching**, **short dead times** and **low losses** while keeping normative like safe isolation and interference immunity.

Infineon helps you **selecting the relevant features** in a gate drivers datasheet, which aspects to cover in your design and layout and how to address EMI topics.



Infineon Technologies AG

# Agenda

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- › Output current
- › Low ohmic output stages
- › Buffer caps
- › Timing
- › UVLO
- › Fast active clamping
- › Layout considerations
- › Portfolio overview and selection tools

# Some suitable applications

## Solar, UPS, Battery Management



- > UPS up to 10 kvA
- > Solar inverter
- > Medium voltage battery management systems

## Telecom – non-isolated DCDC



- > Basestation marco and distributed

## Battery Powered Applications



- > Power tools
- > Light electric vehicles
- > Service robots

## Server & storage



- > Server–Intel/IBM/AMD/ARM
- > Workstation
- > Storage
- > Artificial intelligence

## SyncRec for SMPS HP+LP



- > Telecom and server PSUs
- > Adapter and charger

## Telecom – isolated DCDC



- > Brick converters
- > Protection ICs

## Class-D Audio



- > High-End audio systems
- > Battery powered speakers
- > Smart speakers

## WLS Charging



- > Qi WLS charging solutions
- > A4WP wireless charging solutions

## High-end consumer



- > HE desktop/notebook
- > Gaming
- > Graphic
- > Industrial PC

# Relevant parameter in the Gate-driver's Datasheet:

- > Number of channels
- > Isolation or level-shifter
- > Output current
- > Voltage class
- > Package
  
- > something else... ?



## EiceDRIVER™ 1EDBx275F

**Single-channel isolated gate-driver ICs in 150 mil DSO package**

### Description

EiceDRIVER™ 1EDBx275F is a family of single-channel isolated gate-driver ICs, designed to drive Si, SiC and GaN power switches.

1EDBx275F is available in an 8-pin DSO package with 4 mm input-to-output creepage distance; it provides isolation by means of on-chip coreless transformer (CT) technology.

With tight timing specifications, 1EDBx275F is designed for fast-switching medium-to-high power systems. Excellent common-mode rejection, low part-to-part skew, fast signal propagation and small package size make 1EDBx275F a superior alternative to high-side driving solutions using optocouplers or pulse transformers.

### Features

- Single-channel isolated gate-driver
- 45 ns input-to-output propagation delay with excellent accuracy (+4/-4 ns)
- Separate low impedance source and sink outputs
- Fast clamping of parasitics-induced output overshoots under UVLO conditions
- Fast start-up times and fast recovery after supply glitches
- Optimized UVLO levels (4 V, 8 V, 13 V) for Si, SiC and GaN transistors
- High common mode transient immunity (CMTI > 300 V/ms)
- Available in 8-pin 150mil DSO package
- Qualified for industrial grade applications



### Isolation and safety certificates

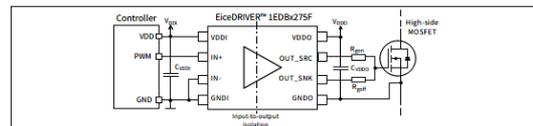
- UL1577 with  $V_{ISO} = 3000 V_{RMS}$  (certification pending)

### Potential Applications

- Server, telecom and industrial Switch-Mode Power Supplies (SMPS)
- EV power modules, motor drives and power tools
- Solar power inverters and Uninterruptible Power Supplies (UPS)

**Table 1 EiceDRIVER™ 1EDBx275F Portfolio**

Part number	Peak source / sink current	UVLO ON / OFF	Isolation certification	Package
1EDB7275F	5.4 A / 9.8 A (for $V_{DD0} = 15V$ )	4.2 V / 3.9 V	UL1577 ( $V_{ISO} = 3000 V_{RMS}$ )	PG-DSO-8
1EDB8275F		8.0 V / 7.0 V		
1EDB9275F		13.7 V / 12.9 V		



**Figure 1 Typical application**

Final Data Sheet  
[www.infineon.com](http://www.infineon.com)

Please read the Important Notice and Warnings at the end of this document

Rev. 2.0  
2020-04-08

# Fast switching SMPS Gate Drivers

## › Relevant parameter in the Gate-driver's Datasheet:

- Output current: what does a certain peak value mean in the application
- Timing: propagation delay, pd mismatch pulse width min, distortion dead-time
- UVLO: threshold and timing
- Clamping: startup behavior

## › Design considerations

## › Layout considerations



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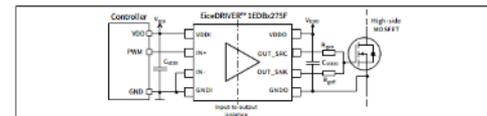
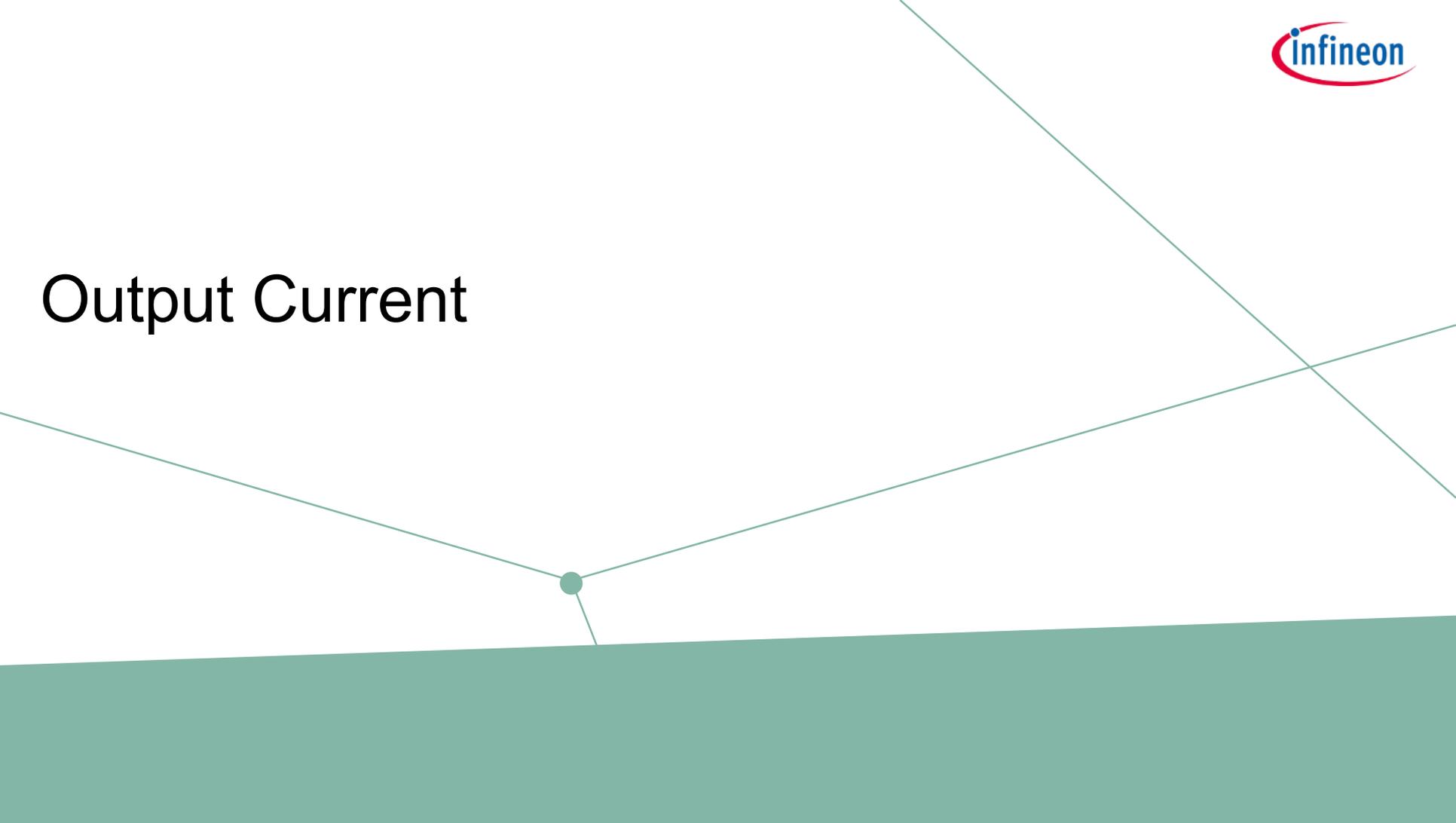


Figure 1 Typical application

Final Data Sheet [www.infineon.com](http://www.infineon.com) Please read the Important Notice and Warnings at the end of this document

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# Output Current



## Gate-driver Datasheets – Output current

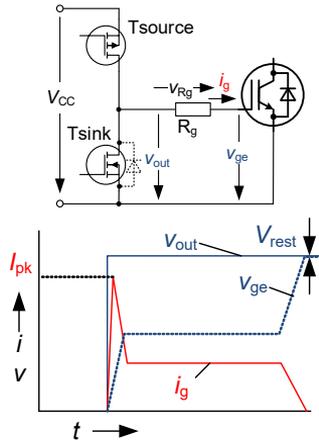
- › Investigate the **output capability** of Infineon isolated products vs. Competitors
  
- › In this investigation
  - **1EDC60I12AH** (typ.  $I_{OH} = 10\text{ A}$ )
  - **1ED3124Mx12H** (typ.  $I_{OH} = 14\text{ A}$ )
  - **Competitor U** (configured as unipolar) (typ.  $I_{OH} = 17\text{ A}$ )
  
- › Lets investigate switching behavior of the devices and their capabilities
  - with capacitive load
  - with an IGBT7 module (**FF900R12ME7\_B11**)

Observe the strengths and weaknesses of each product



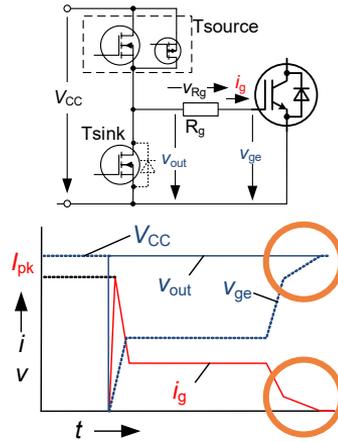
# Comparison of selected output section topologies?

## P-channel N-channel



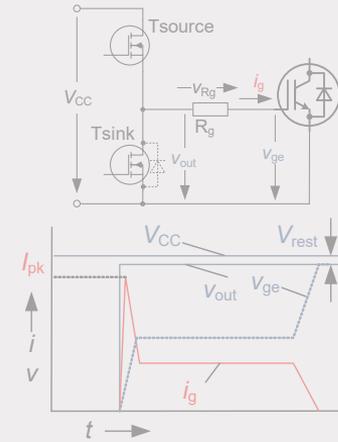
- > Strong on-current@Miller
- > Rail2Rail

## (P+N)-channel N-channel



- > High  $R_{DS(on)}$  p-channel can bring more losses
- > Weak on-current@Miller
- > Rail2Rail

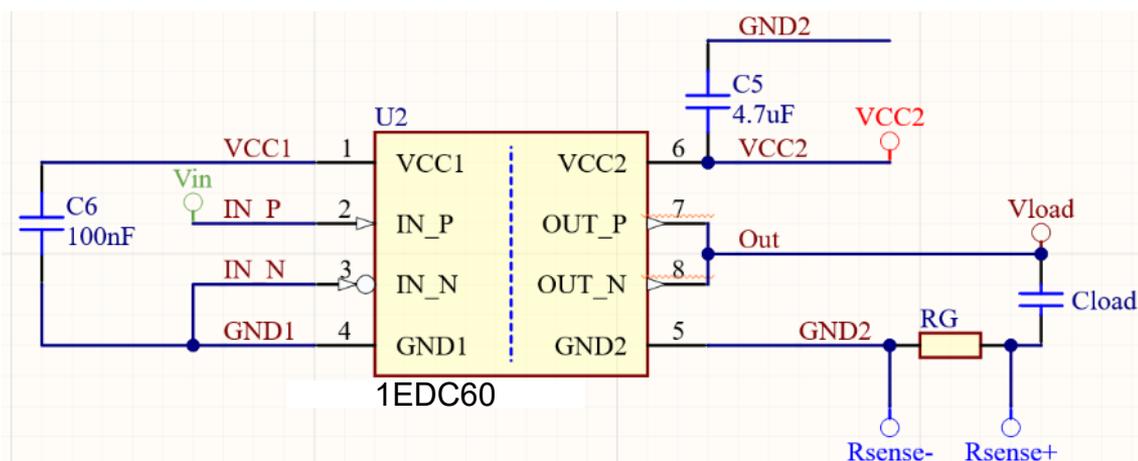
## N-channel N-channel



- > Voltage remainder for on-state (no rail2rail)
- > Needs over-drive -> bad effects and work-arounds

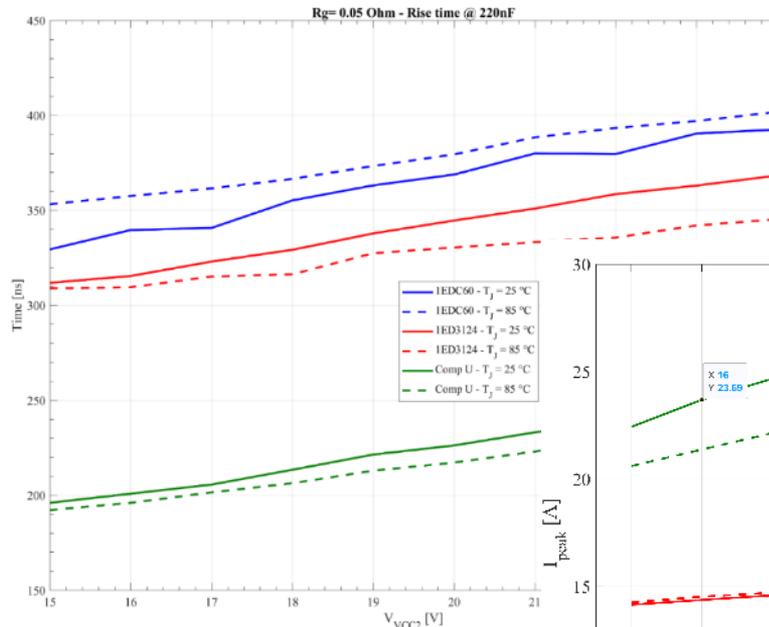
## Capacitive load turn-on – sample test setup

- > The gate loop was kept low inductive
- > Capacitive load:  $C_{load} = 220\text{nF}$
- >  $R_g$  (also used for current measurement) =
  - $0.05\ \Omega$  (to observe the unimpeded gate driver behavior)
  - $1.00\ \Omega$  (at the lower limit of the range where such gate drivers are fully exploited)
  - $10.0\ \Omega$  (quite large value for such gate drivers, at the upper feasibility limit)
- >  $V_{VCC2}$  = increasing from 15V to 24V, in 1 V steps
- >  $T_j = 25^\circ\text{C}$  &  $85^\circ\text{C}$

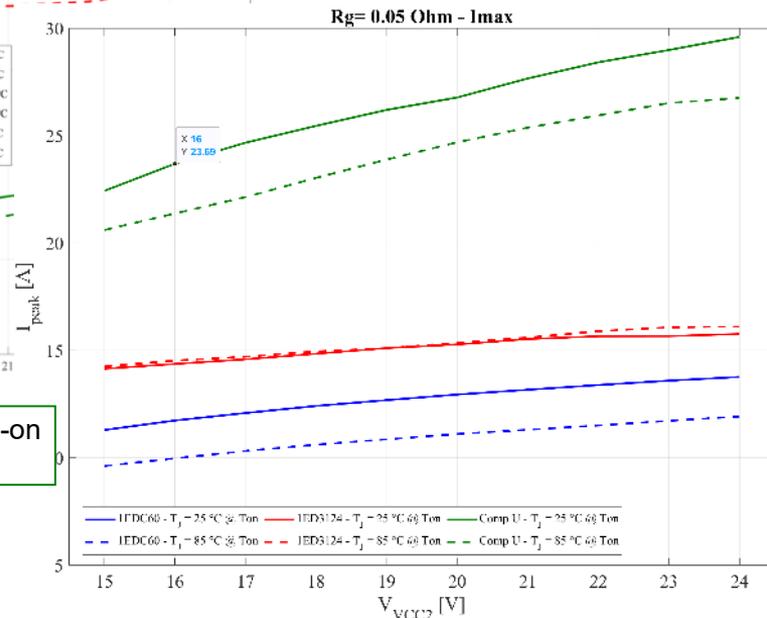


# Capacitive load – Rise time & I<sub>max</sub> – R<sub>g</sub> = 0.05 Ohm

- > Rise time (10% ↑ 90%)
- > Peak output current (w/o inductive overshoots)
  - Blu: 1EDC60
  - Red: 1ED3124
  - Grn: Comp.
  - Solid: 25°C —
  - Dashed: 85°C - - -
- > C<sub>load</sub> = 220nF
- > Competitor: bootstrap circuit may boost the n-channel performance at turn-on for a short time

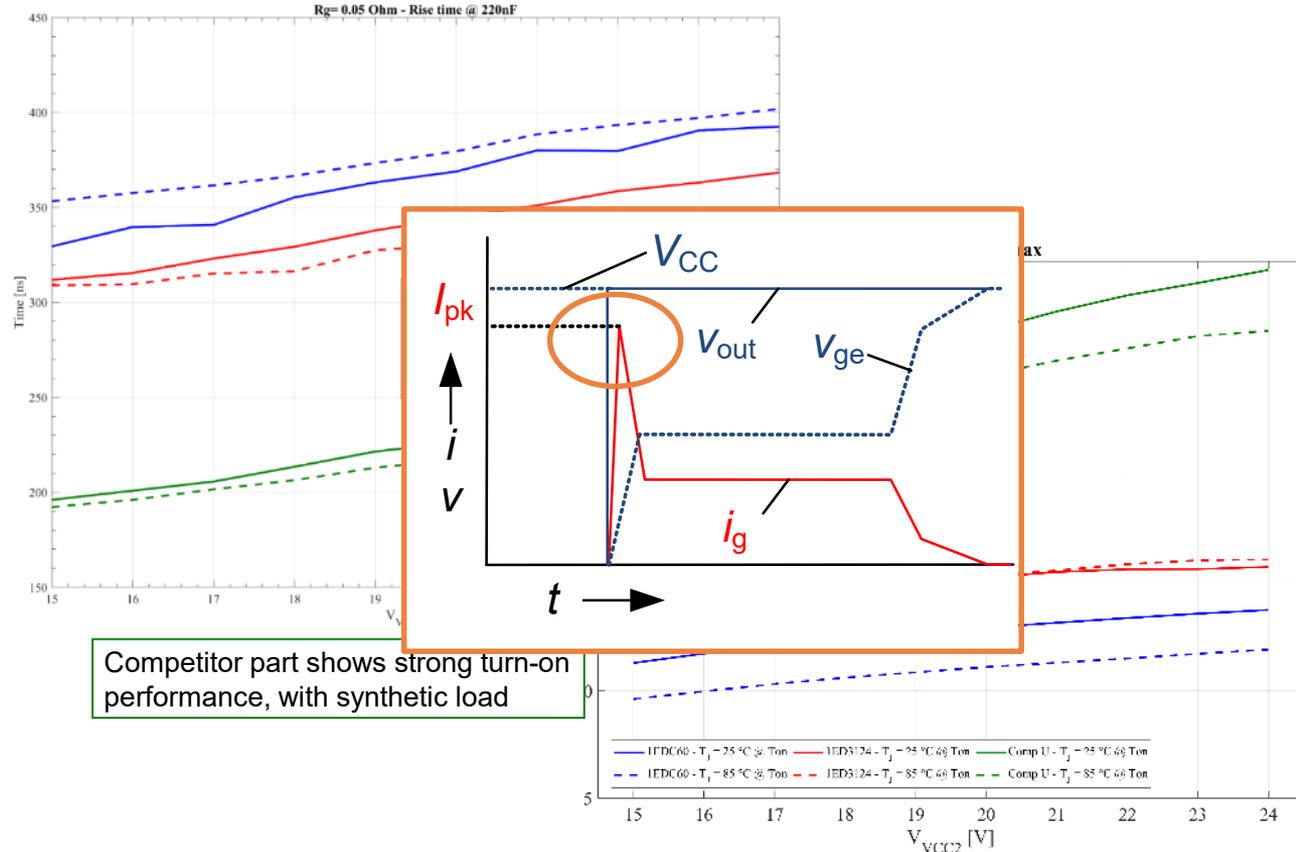


Competitor part shows strong turn-on performance, with synthetic load



# Capacitive load – Rise time & $I_{max}$ – $R_g = 0.05 \text{ Ohm}$

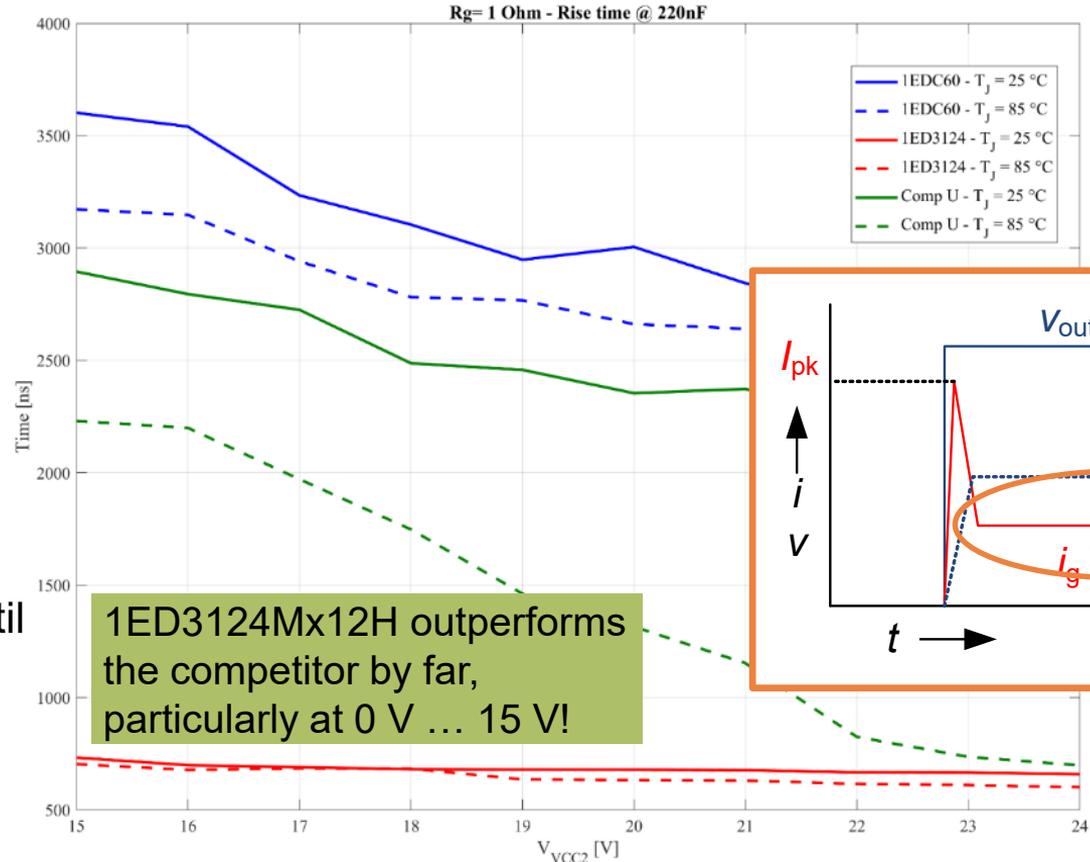
- > Rise time (10%  $\uparrow$  90%)
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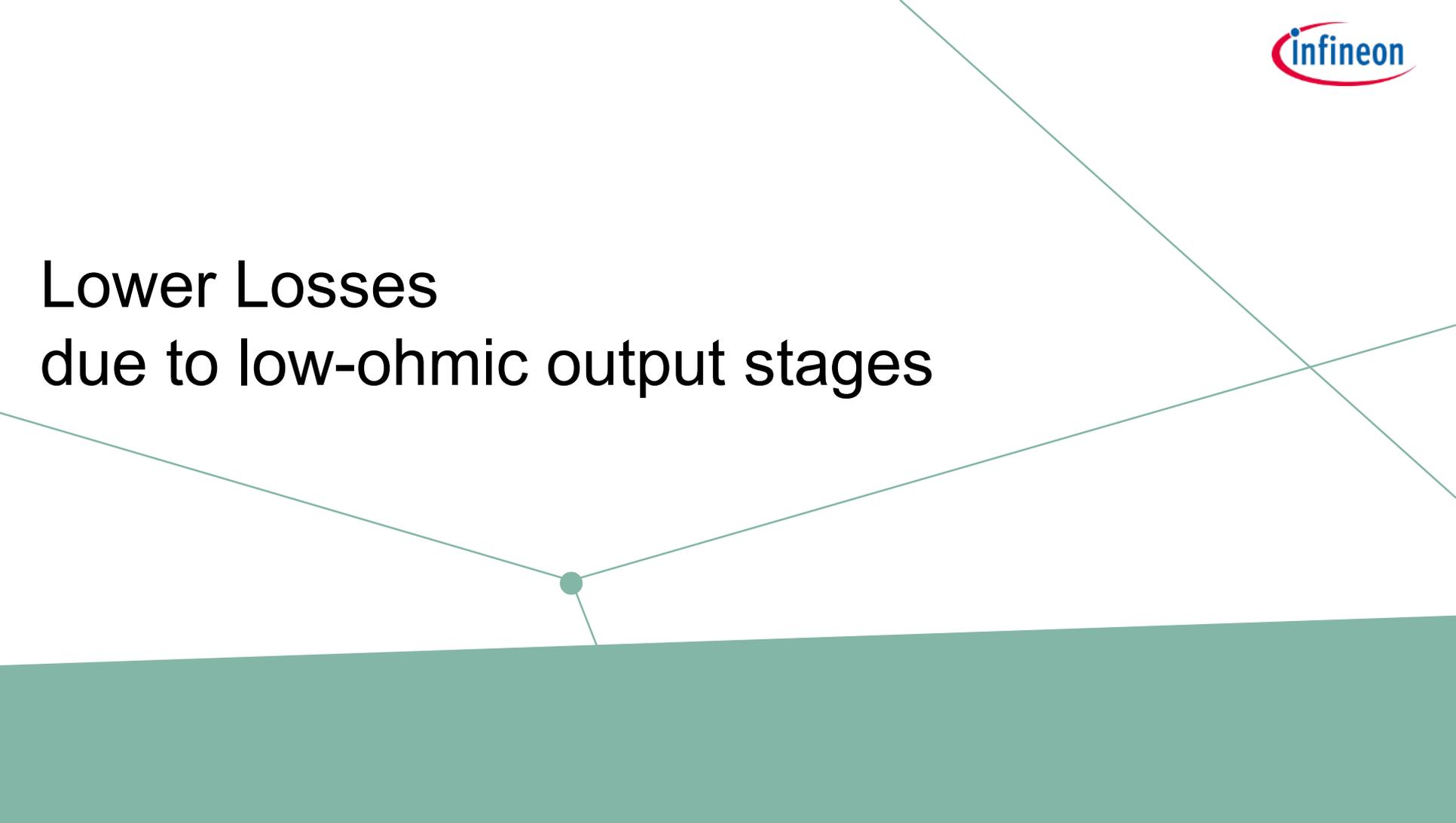
Competitor part shows strong turn-on performance, with synthetic load

# Capacitive load – Rise-time – $R_g = 1 \text{ Ohm}$

- > Rise time (10%  $\uparrow$  90%)
  - Blu: 1EDC60
  - Red: 1ED3124
  - Grn: Comp.
  - Solid: 25°C —
  - Dashed: 85°C - - -
  
- >  $C_{load} = 220\text{nF}$
  
- > The strong p-channel of 1ED3124MC12H can deliver turn-on current until the end!



Lower Losses  
due to low-ohmic output stages

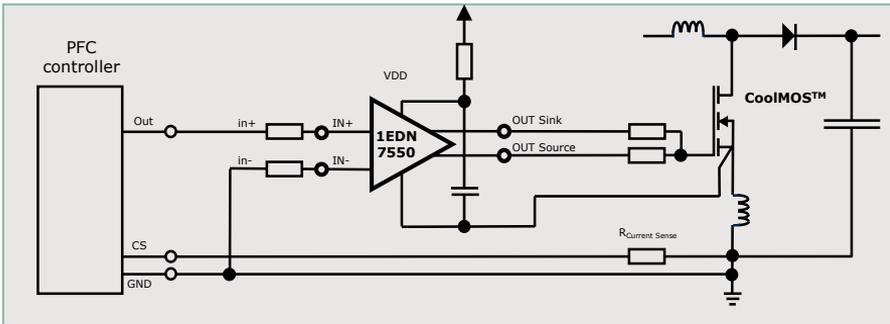
The slide features several decorative green elements: a thin line starting from the top right and extending towards the center; another thin line starting from the left and meeting the first one at a small green circle; a third thin line extending from the right towards the same circle; and a large, solid green shape at the bottom of the slide that tapers to a point at the center where the lines meet.

# Taking advantage of true rail-to-rail low-ohmic output stages: example: 1EDN7550 ( special hint → [TDI: true-differential input](#) )

## Compatible



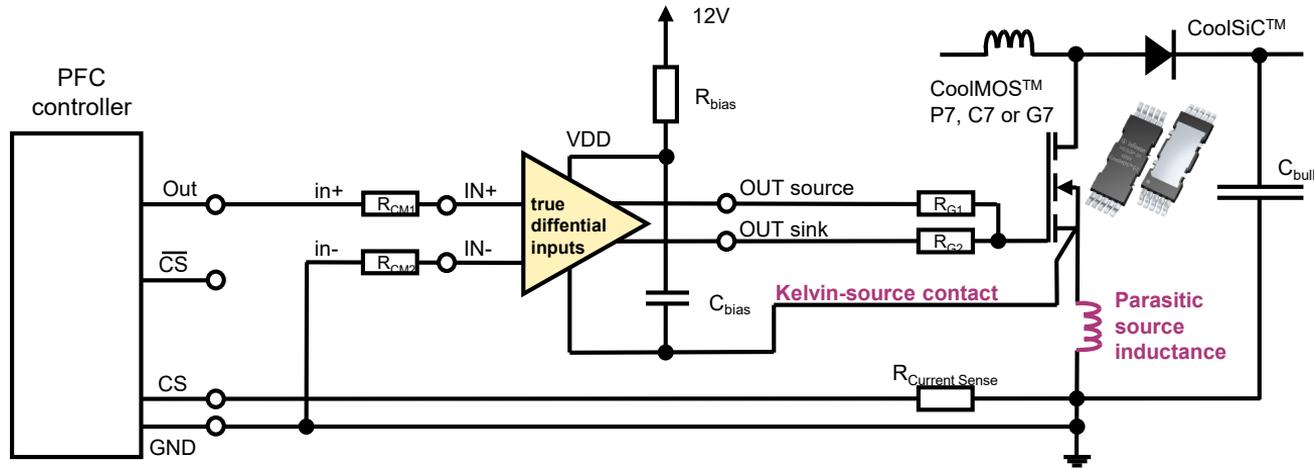
- > Packages: DSO TSSOP WSON
- > Power: 2x +/-5A
- > Pace: 19 ns propagation delay
- > Precision: 1 ns channel-to-channel Propagation Delay Matching
- > Price: Competitive



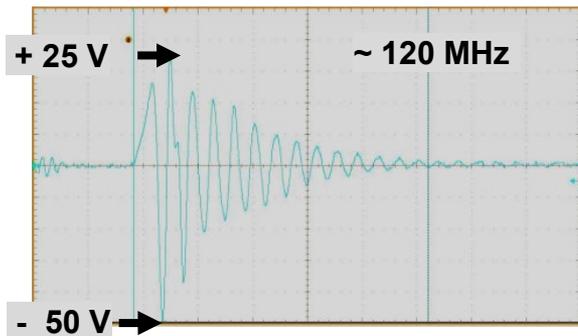
## Better

- > Truly low-ohmic output stages:
  - Least internal power dissipation
  - More effective gate-drive power
  - **0.65  $\Omega$  P-FET / 0.5  $\Omega$  N-FET**
- > -10 V Input robustness:
  - Crucial noise margin
  - to safely drive pulse transformers
- > 5 A reverse current robustness
  - No need for Schottky clamping diodes
  - Higher power density, lower BoM
- > 8V UVLO Protection:
  - Fast and reliable SuperJunction and
  - Standard-Level MOSFET protection

# Quick intro: Driving the MOSFETs with True Differential Inputs



**GND-shift:**



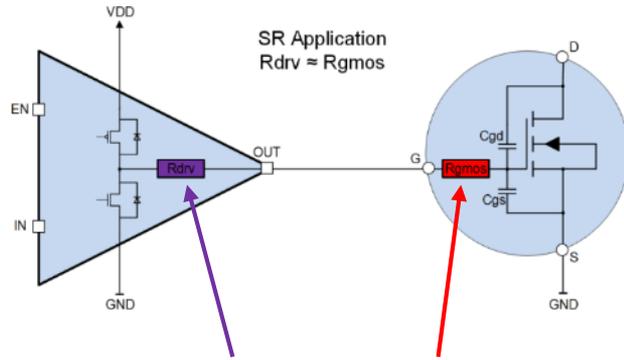
**PFC controller  
vs.  
Gate driver IC**

**Gate driver with  
differential inputs:**

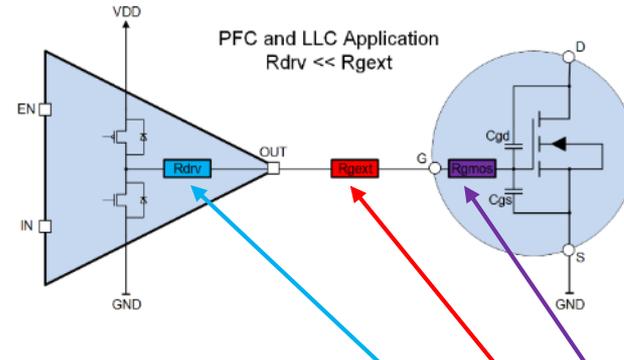
- > Robust against  $\pm 150\text{ V AC}_{pk}$  GND-shifts
- > Small SOT-23  
Tiny TSNP-6

# Low Rdson output stage extends application coverage

The theory behind: How is the driving power distributed



$$P_{total} = \frac{P_{total}}{R_{drv} + R_{gmos}} (R_{drv} + R_{gmos})$$



$$P_{total} = \frac{P_{total}}{R_{drv} + R_{gext} + R_{gmos}} (R_{drv} + R_{gext} + R_{gmos})$$

$$P_{total} = C_{g\_tot} * V_{DD}^2 * f_{SW} = Q_{g\_tot} * V_{DD} * f_{SW}$$

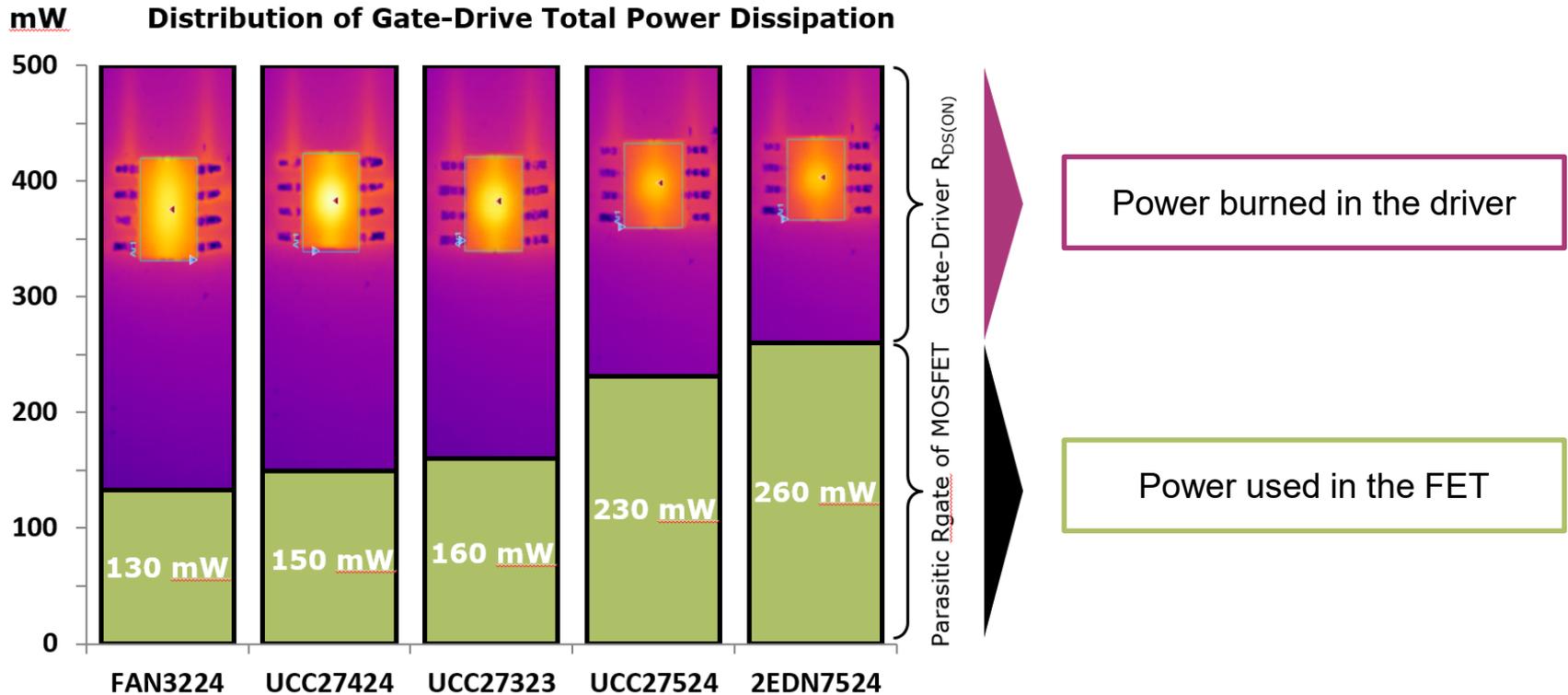
$C_{g\_tot}$  = Total Gate Capacitance

$Q_{g\_tot}$  = Total Gate Charge

$V_{DD}$  = Driver Supply Voltage

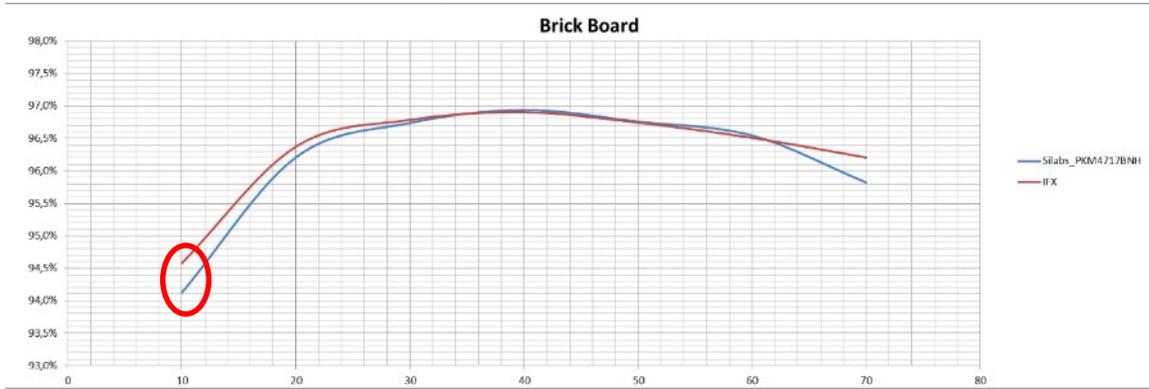
$f_{SW}$  = Switching Frequency

# Taking advantage of true rail-to-rail low-ohmic output stages: 1EDN up to 2x more effective gate-drive power



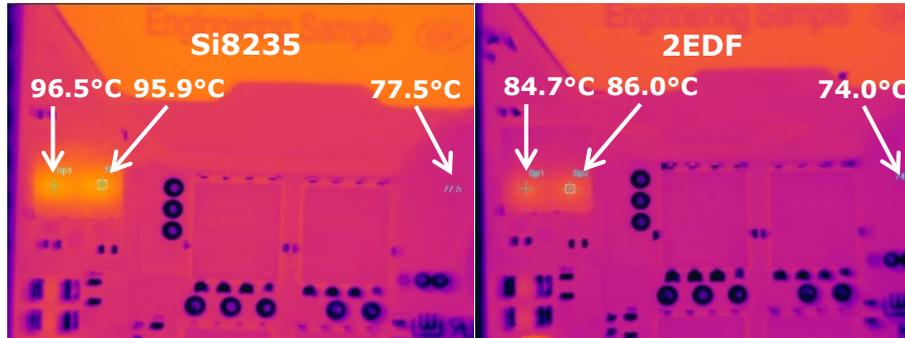
**Use-Case:** Synchronous Rectification with 50% duty-cycle, 250 kHz  
2x 3 OptiMOST™ 1mOhm 30V in parallel, 2-layer JEDEC 51-7 PCB

# Driver $P_D$ comparison on 750W 1/4Brick: IFX 2EDF vs. Silabs Si8235



## Cooler Driver Advantages:

- > Flexibility in thermal design
- > Can drive faster/more FETs within thermal budget
- > Better reliability



## Use-Case:

- > Sync. Rectification
- > 2x 2 OptiMOS BSC010NE2LSI  
1m $\Omega$  / 25V in parallel,
- > 0.5 $\Omega$  / 12nF RC load equivalent
- > fs=200kHz,
- > Vgs=8V

## Gate-driver Datasheets – Output current – conclusions

- › Datasheet-test-conditions can be misleading
  - Synthetic tests, as used for datasheets with unrealistically small capacitors, can be misleading and some competitors might appear better.
  
- › Gate driver ICs do only show their realistic behavior when paired with a power transistor.
  
- › It is most important to select gate drivers having a **strong p-channel FET** for turn-on, such as the X3-Comapct family.

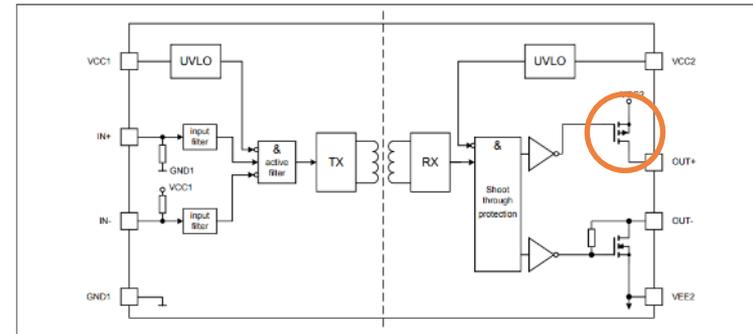


Figure 2 Block diagram separate source and sink output variants

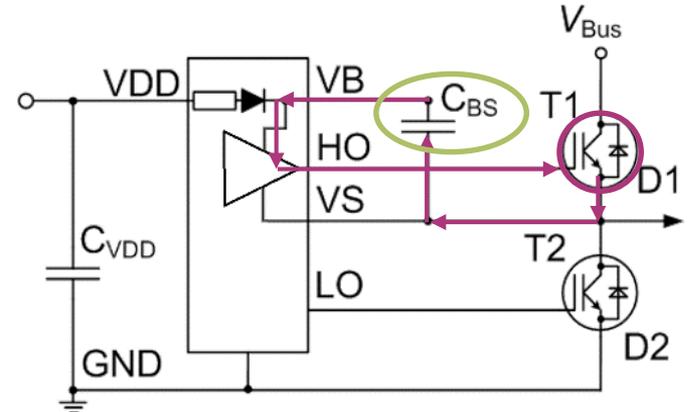
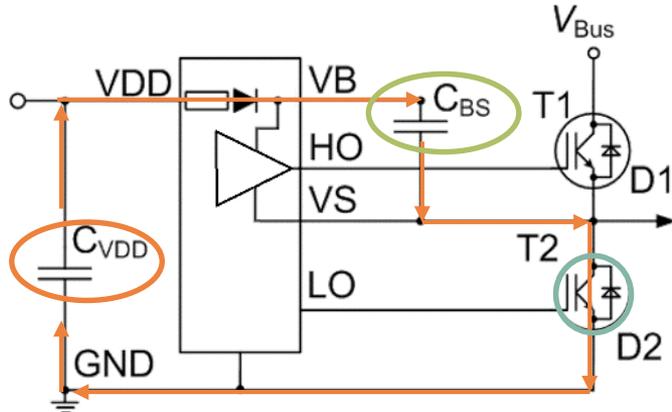
# Buffer Caps



# Understanding the importance of by-pass capacitor $C_{BS}$

- ›  $C_{BS}$  charges only during LowSide-FET ON-time
- › Energy transfer between caps  $C_{VDD}$  and  $C_{BS}$  - not from supply !
  - Requires low ESR caps and low impedance connections.

- ›  $C_{BS}$  supplies gate current during HighSide-FET ON-time
- › Energy transfer between caps  $C_{GD}$  and  $C_{BS}$ !



# Bypass capacitor: Comparison of different $C_{BS}$ values

## > Driver supply system in more detail

- $C_{BS}$  charges  $C_{load}^{(*)}$
- $V_{CBS}$  drops
  - (beware of UVLO,  $V_G$  !)
- $\Delta V_{dd_{drv}} = V_{dd_{drv}} * \frac{C_{load}}{C_{BS}}$

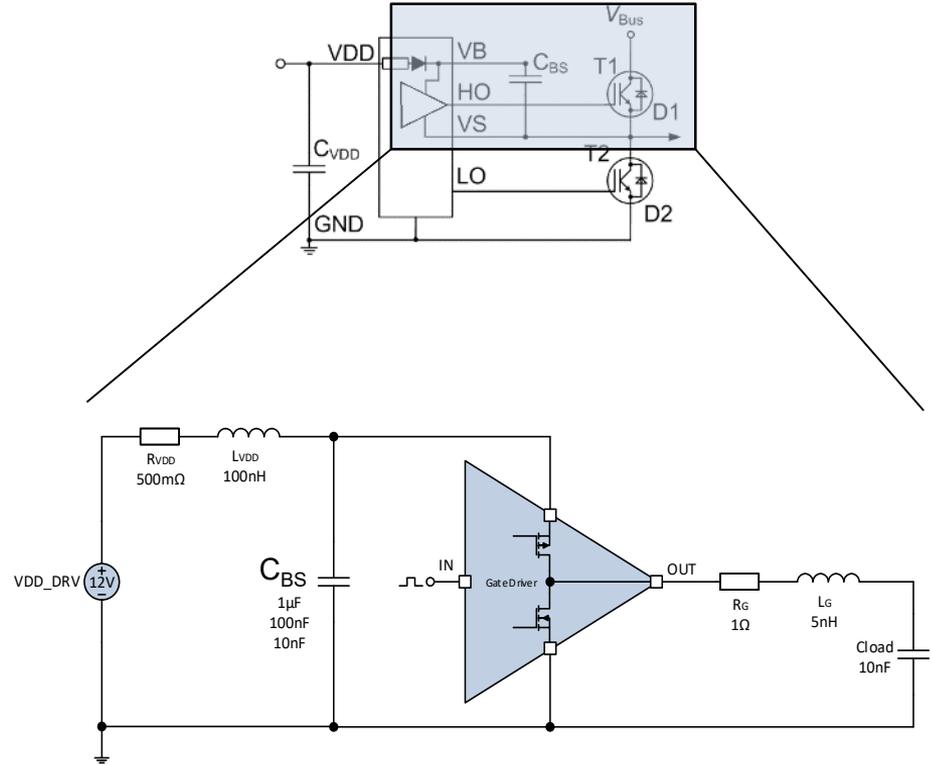
- If we require:

$$\Delta V_{dd_{drv}} = 5\%$$

- We need:

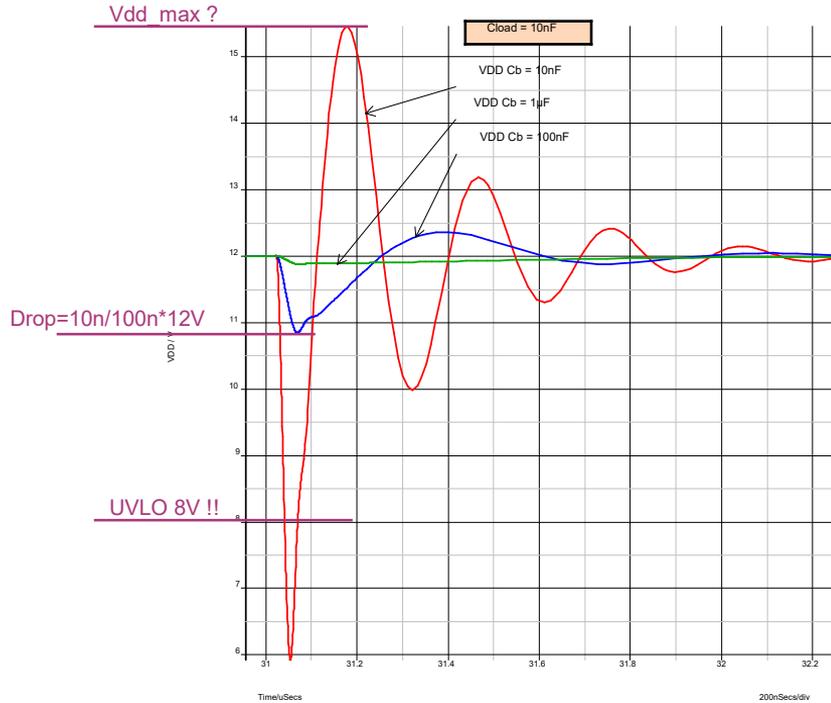
$$C_{BS} = 20 * C_{load}$$

$$(*) C_{load} = \frac{QG}{V_{GS}}$$

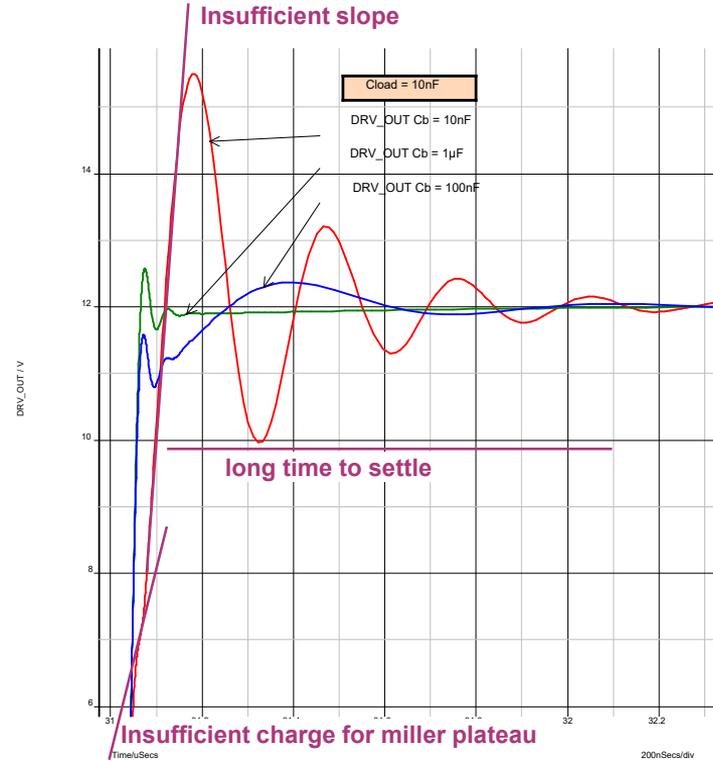


# Bypass capacitor: Comparison of different $C_{BS}$ values

Simulation driver supply voltage



Simulation driver output voltage



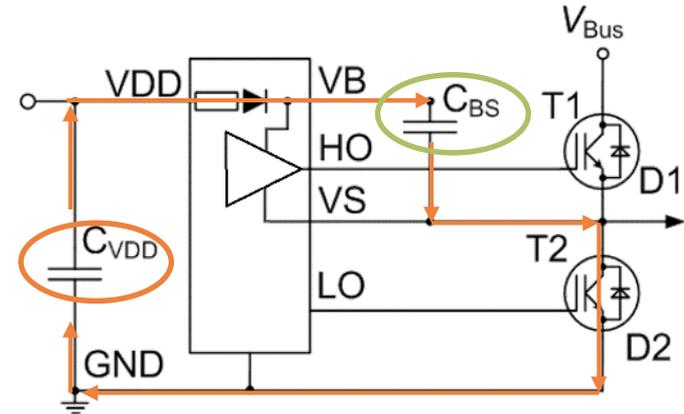
## Bypass capacitor at the supply side: $C_{VDD}$

› Same applies for relation  $C_{VDD}/C_{BS}$

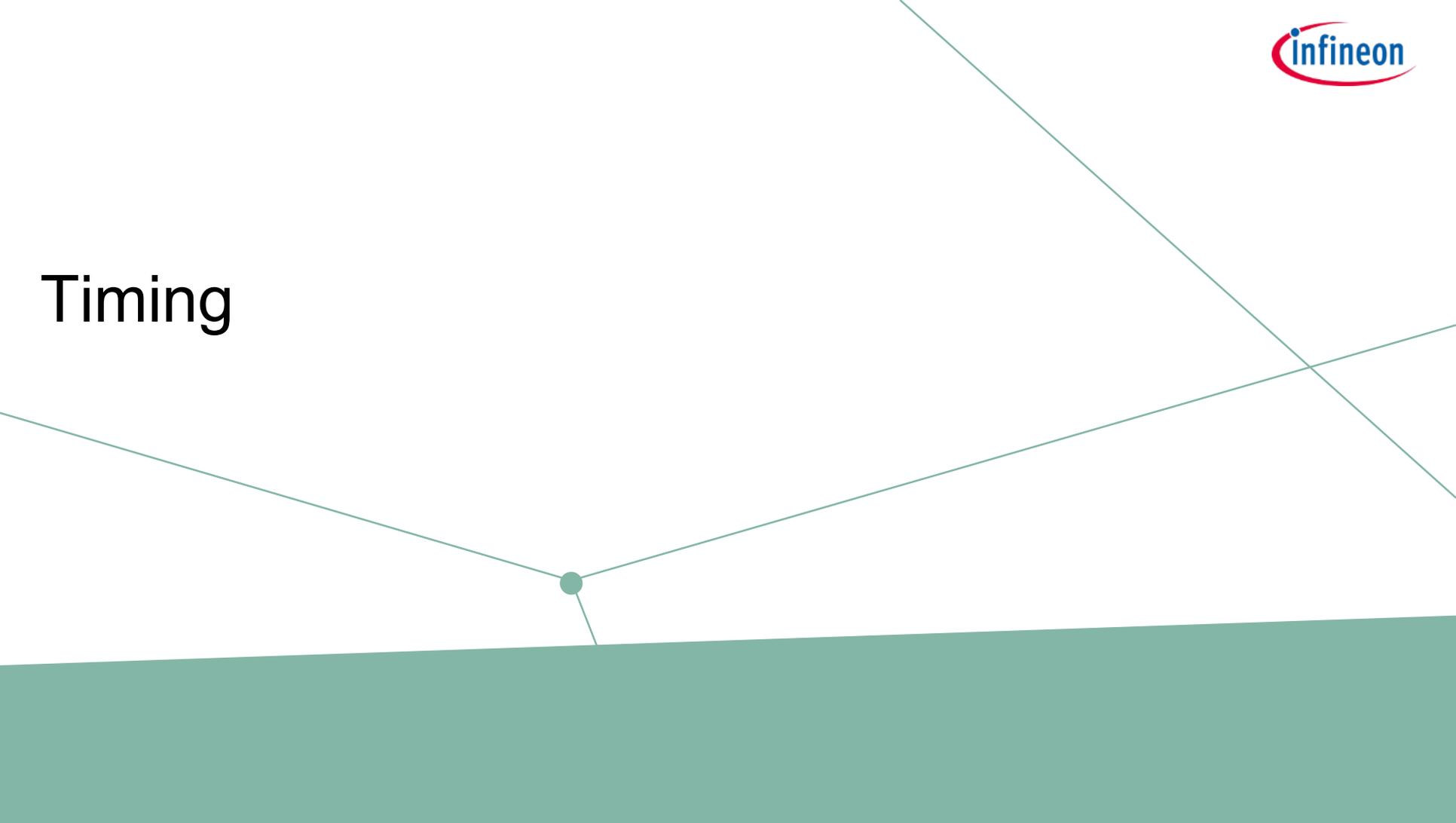
– Select low ESR,

$$C_{VDD} \geq 20 \cdot C_{BS}$$

- Place  $C_{VDD}$  close to Vdd-pin
- Avoid leakage inductance in the path from supply to  $C_{VDD}$  to avoid ringing.



Timing



# How does precision timing help ?

- > Short and precise dead-times lead to more efficient designs.
  - During dead time no energy is transferred.
  - Too short DT leads to risk of shoot-through

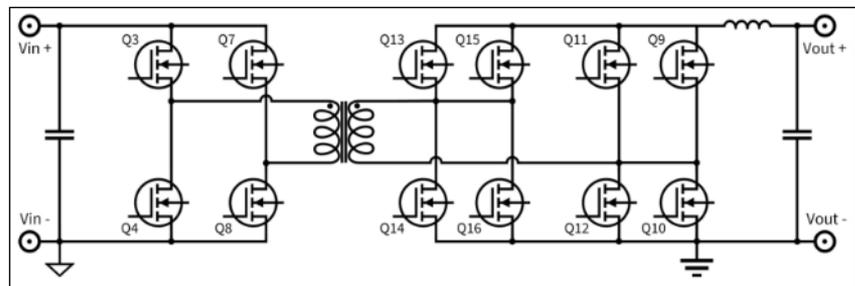
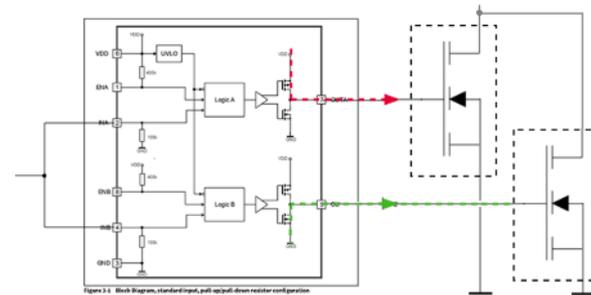
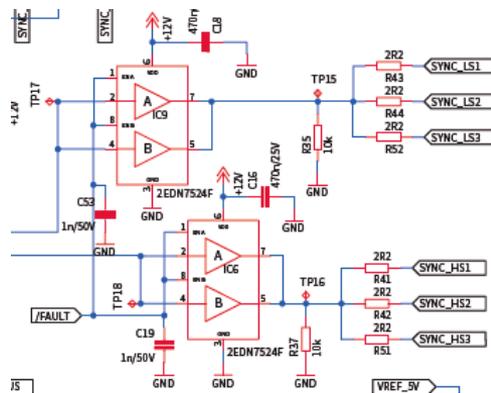


Figure 2 Topology of the FB-FB rectifier

- > Precise timing enables
  - paralleling of PowerFETs
  - paralleling of Drivers



# 1EDB Family cross-reference

## All in 150mil 8-pin DSO package and with same pinout



All Infineon 1-channel galvanically isolated gate-driver ICs can be found at: <https://www.infineon.com/cms/en/product/power/gate-driver-ics/high-side-drivers/>

Part number	Isolation		Typ. V <sub>DDO</sub> UVLO		Max. V <sub>DD</sub>	Typ. Input Filter Time [ns]	Typ. Propagation Delay [ns]	Propagation delay accuracy over temperature & production	Typ. output current		data sheet		
	Certification	Rating	turn on	turn off					V <sub>DDO</sub> = 15V, V <sub>out</sub> = 0 V, @ RT	Source		Sink	
1EDB6275F	UL1577 (pend.)	V <sub>ISO</sub> = 3000 V <sub>rms</sub>	12.2 V	11.5 V	20 V	19 ns	45 ns	+/- 4 ns	5.4 A <sub>peak</sub>	-9.8 A <sub>peak</sub>	3.8.20, Rev. 2.1		
1EDB7275F			4.2 V	3.9 V									
1EDB8275F			8.0 V	7.0 V									
1EDB9275F			14.9 V	14.4 V									
	<b>New</b>												
1EDI20N12AF	n.a.	V <sub>ISO</sub> = ± 1200 V <sub>DC</sub>	9.1 V	8.5 V	35 V	40 ns	115 ns (on)	+ 23 / - 25 ns	4 A <sub>peak</sub>	-3.5 A <sub>peak</sub>	1.6.15, Rev. 2.0		
1EDI60N12AF			120 ns (off)	@ 25°C					10 A <sub>peak</sub>	-9.4 A <sub>peak</sub>			
1ED3124MU12F	UL 1577	V <sub>ISO</sub> = 3000 V <sub>rms</sub>	12.5 V	10.5 V		30 ns	90 ns	14 ns @ 25°C	13.5 A <sub>peak</sub>	-14 A <sub>peak</sub>	20.10.20, Rev. 2.0		
	<b>New</b>												
UCC5320SC	UL 1577 and VDE 0884-11	V <sub>ISO</sub> = 3000 V <sub>rms</sub>	12 V	11 V	33 V	n/a	60 ns	+ 12 ns (on) + 15 ns (off)	4.3 A <sub>peak</sub>	-4.4 A <sub>peak</sub>	SLLSER8F – JUNE 2017– REVISED JANUARY 2019		
UCC5350SB		V <sub>IOTM</sub> = 4242 V <sub>peak</sub>	8.7 V	8.0 V					65 ns	+ 35 ns (on/off)		8.5 A <sub>peak</sub>	-10 A <sub>peak</sub>
UCC5390SC			12 V	11 V					17 A <sub>peak</sub>	-17 A <sub>peak</sub>			
NCD57080C	n.a.	3750 V <sub>rms</sub>	12.9 V	12 V	32 V	40 ns	60 ns	+/- 15 ns	8 A <sub>peak</sub>	-8 A <sub>peak</sub>	Mar.-20, Rev. 0		
STGAP2HSMTR	n.a.	V <sub>IOTM</sub> = 6000 V <sub>peak</sub>	9.1 V	8.4 V	26 V	20 ns	75 ns	+/- 20 ns	4 A <sub>peak</sub>	-4 A <sub>peak</sub>	DS13393 Rev 2		

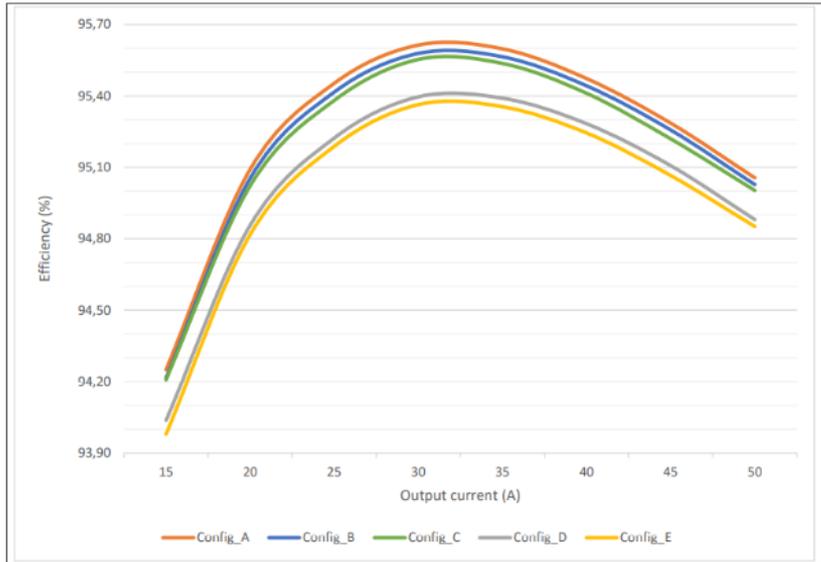
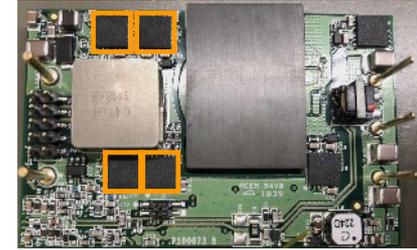


# Example: 600 W quarter-brick 48 V to 12 V full-bridge

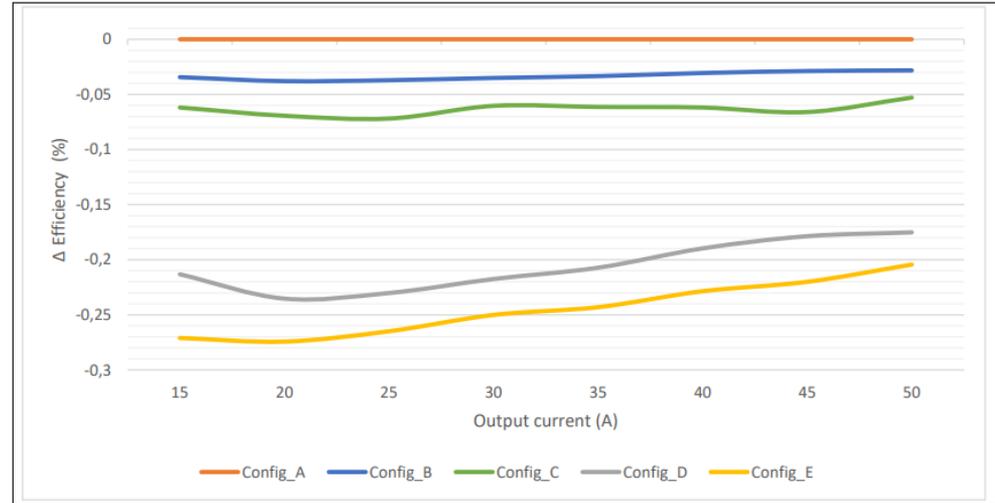
See Application note: EiceDRIVER™ 2EDF7275K in telecom bricks

**Table 3** Dead-time configuration settings for the efficiency measurements

Configuration	DT1	DT2	Difference to Config_A
Config_A	70 ns	40 ns	-
Config_B	75 ns	45 ns	+ 5 ns
Config_C	79 ns	49 ns	+ 9 ns
Config_D	101 ns	71 ns	+ 31 ns
Config_E	108 ns	78 ns	+ 38 ns

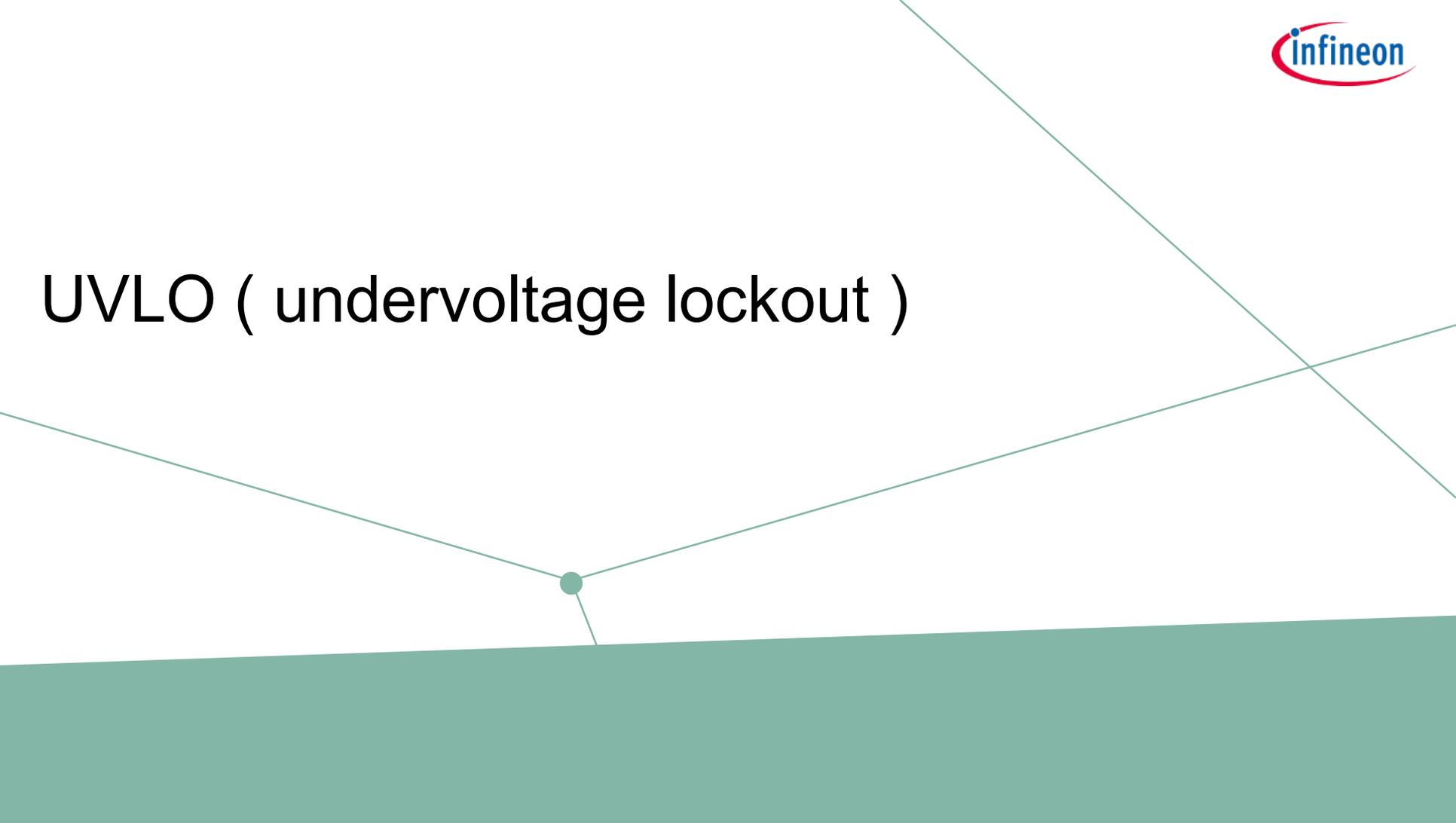


**Figure 15** Efficiency measurement of the 600 W QB 48 V to 12 V FB-FB evaluation board at 48 V DC input voltage for the different dead-time configuration settings



**Figure 16** Differential efficiency measurement of the 600 W QB 48 V to 12 V FB-FB evaluation board at 48 V DC input voltage for the different dead-time configuration settings

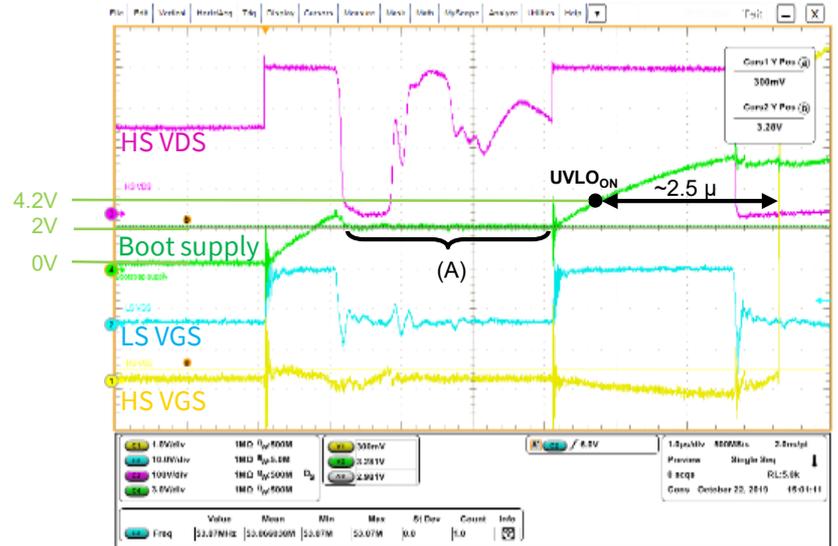
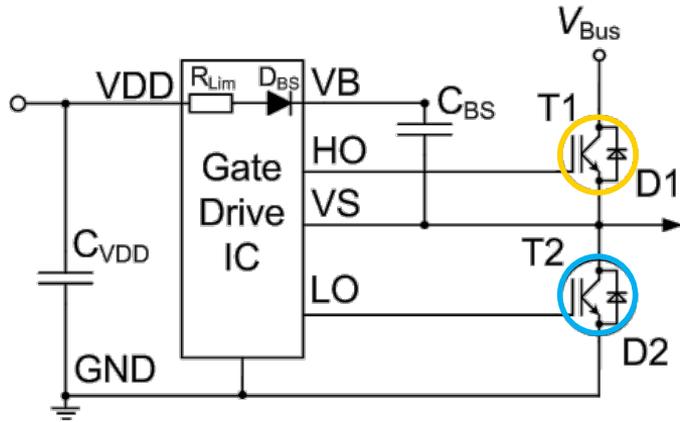
UVLO ( undervoltage lockout )

The slide features several decorative green elements: a thin line starting from the top center and extending towards the right; another thin line starting from the top right and extending towards the center; a third thin line starting from the left edge and extending towards the center; a fourth thin line starting from the center and extending towards the bottom center; and a large, solid green shape at the bottom of the slide that tapers slightly towards the right.

# 1EDB fast reaction time to UVLO events

## Relevance in the end application – Bootstrap systems

- › UVLO protects the FET from linear mode, so its level need to meet  $V_{th}$
- › Bootstrap issues during Startup, or burst-mode, while...
  - LS FET is switching
  - HS FET isn't switching, still in UVLO

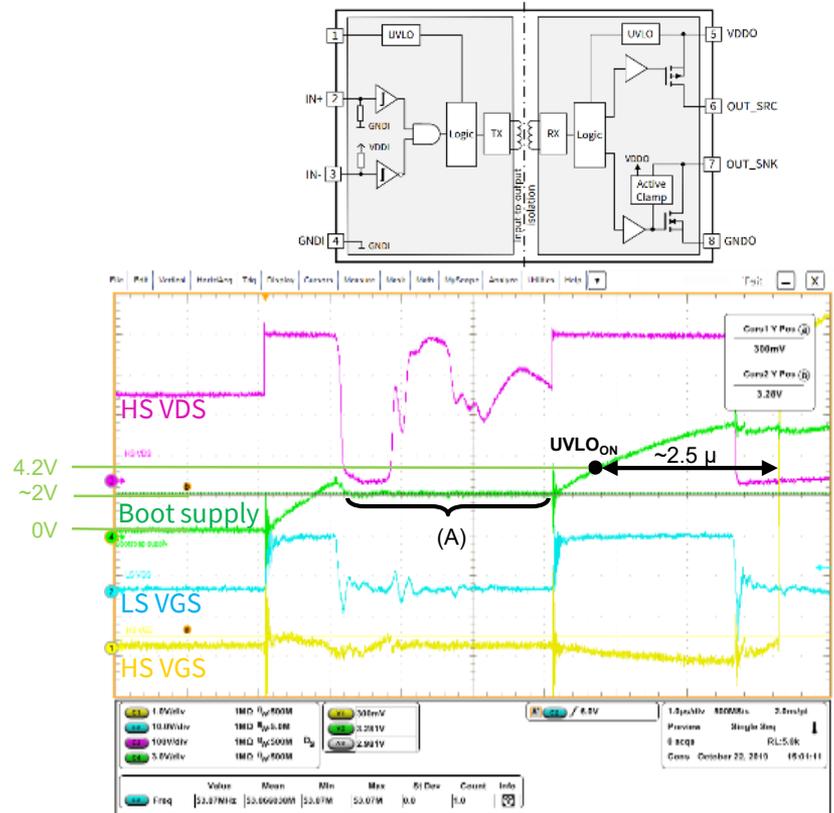


Example: burst-mode in [600W LLC eval board](#) tested with 1EDB7275F

# 1EDB fast reaction time to UVLO events

## Relevance in the end application – Bootstrap systems

- > The start-up time in the datasheet depends on
  - the UVLO block activation time
  - the internal logic start-up time
- > Here, the UVLO start-up time
  - measured  $\sim 2.5\mu\text{s}$
  - is lower than
  - datasheet specification  $5\mu\text{s}$since the internal logic has already started during the flat curve (A) and is ready to switch once the supply hits  $\text{UVLO}_{\text{ON}}$



Example: burst-mode in [600W LLC eval board](#) tested with 1EDB7275F

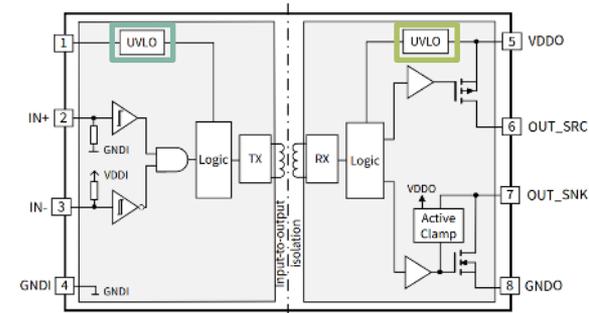
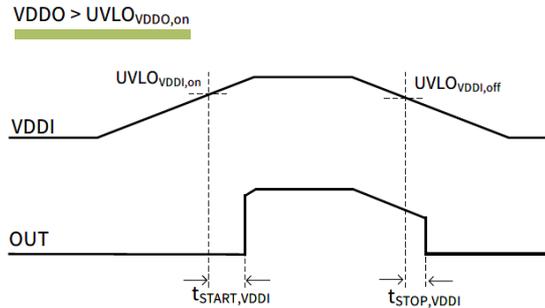
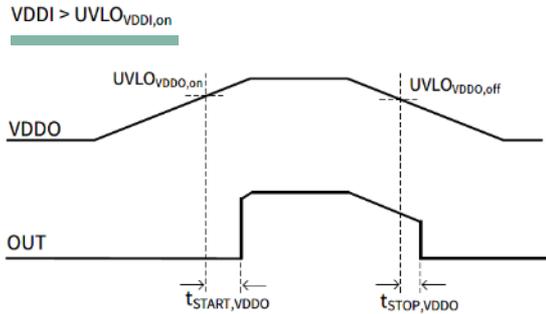


# 1EDB fast reaction time to UVLO events

## Start-up and deactivation times

### > Datasheet values:

Input-side start-up time	$t_{\text{START,VDDI}}$	-	3	-	$\mu\text{s}$	see <b>Figure 8</b>
Input-side deactivation time	$t_{\text{STOP,VDDI}}$	-	300	-	ns	see <b>Figure 8</b>
Output-side start-up time	$t_{\text{START,VDDO}}$	-	5	-	$\mu\text{s}$	see <b>Figure 9</b>
Output-side deactivation time	$t_{\text{STOP,VDDO}}$	-	125	-	ns	see <b>Figure 9</b>



# 1EDB fast reaction time to UVLO events

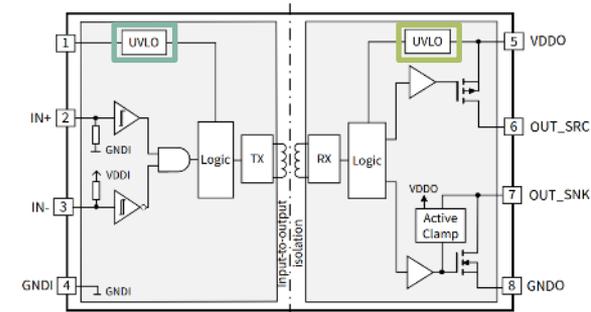
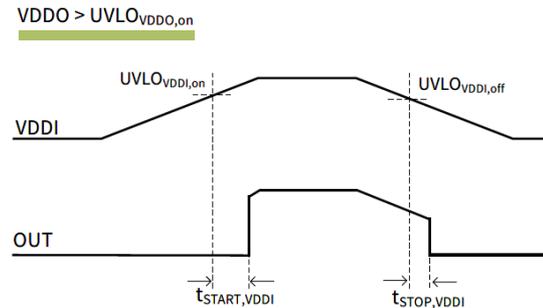
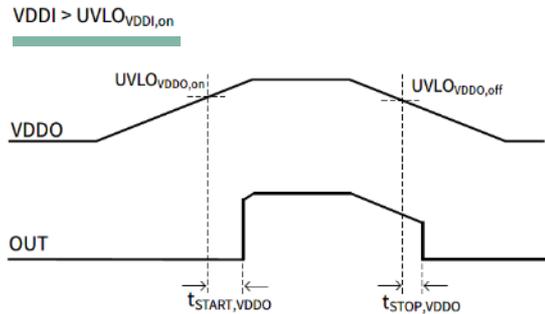
## Start-up and deactivation times

### › Datasheet values:

Input-side start-up time	$t_{START,VDDI}$	-	3	-	$\mu\text{s}$
Input-side deactivation time	$t_{STOP,VDDI}$	-	300	-	ns
Output-side start-up time	$t_{START,VDDO}$	-	5	-	$\mu\text{s}$
Output-side deactivation time	$t_{STOP,VDDO}$	-	125	-	ns

The **input timing** differs between the chips, but  
The **output timing** of all EiceDRIVER™ 2EDi is the same

If the input pulse is sent after  $5\mu\text{s}$ , the driver will react immediately since it is ready. If the pulse is not synchronized and has been set high before, a random  $1.6\mu\text{s}$  inaccuracy has to be considered on top due to the repetition scheme



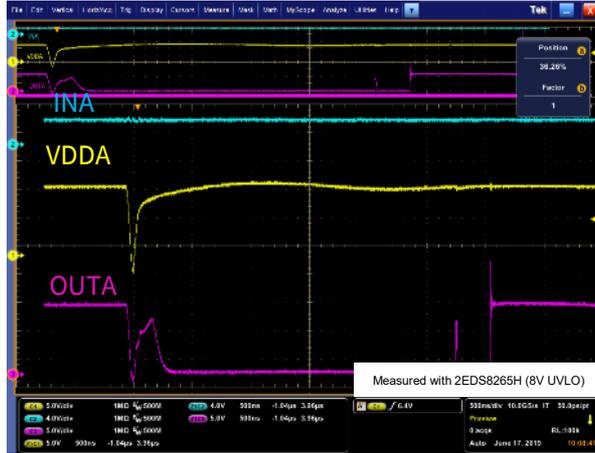
# 1EDB fast reaction time to UVLO events

## Relevance in the end application – Reaction to **glitches** (1/2)

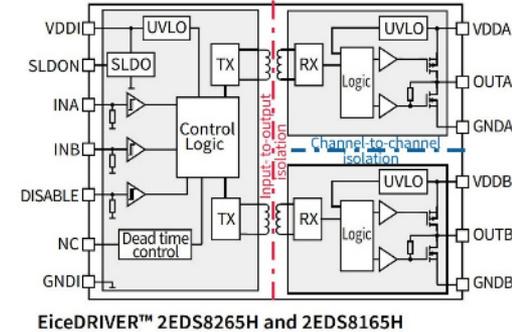
Output-side deactivation time	$t_{STOP,VDDO}$	-	125	-	ns	see <b>Figure 9</b>
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Glitches of few of ns (switching noise)  
filtered out



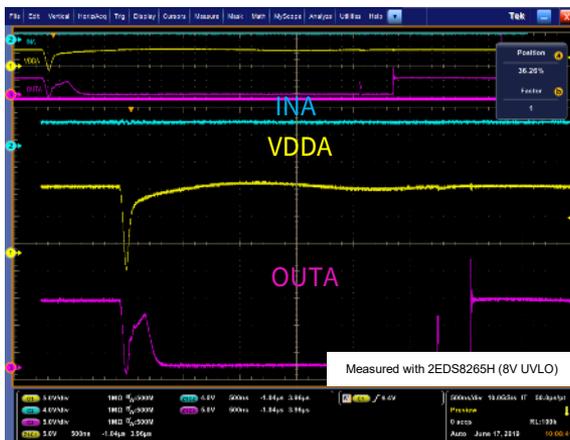
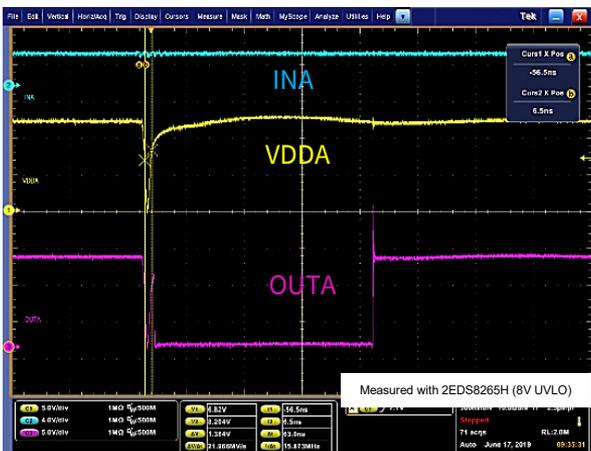
Glitches longer than hundreds of ns  
pass through



# 1EDB fast reaction time to UVLO events

## Relevance in the end application – Reaction to glitches (2/2)

- › For glitches being able to deactivate the UVLO-block, the reaction time of the drivers depends on how fast, how deep and how long the glitch is.
  - The **minimum** reaction time of the driver is given by the **UVLO block activation** (~2.5µs)
  - The **maximum** reaction time of the driver is given by the **maximum start-up time** (~5µs) (UVLO+LogicBlock).

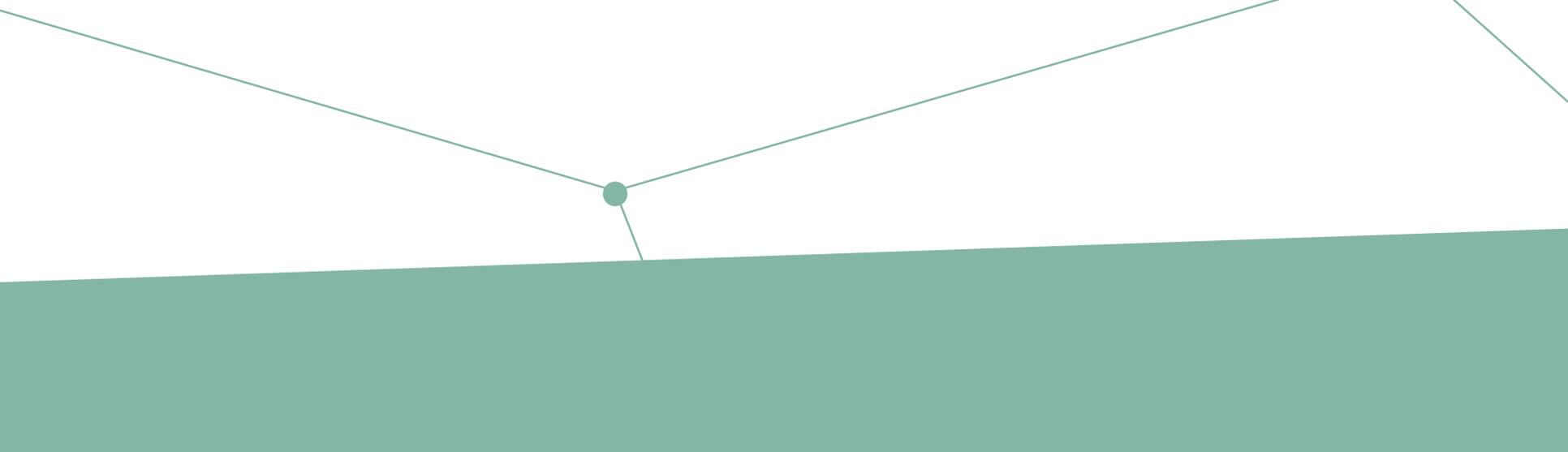


- › 1EDBx275F and 2EDi are able to react within one pulse of 5µs or less to supply drop, e.g. due to noise, enabling fast recovery of normal system operation

### › Fast UVLO reaction times...

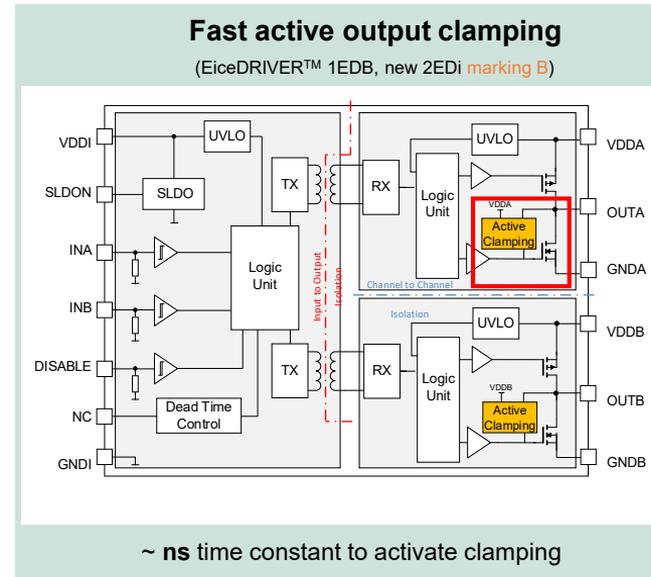
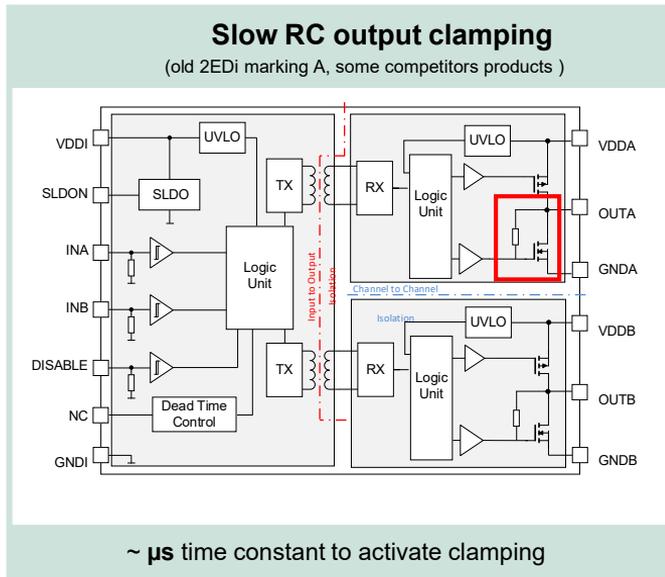
- › enable fast recovery of normal system operation
- › helps ensuring stable system operation
- › especially important, e.g., in high-density brick applications to keep the output regulation.

# Fast active output clamping



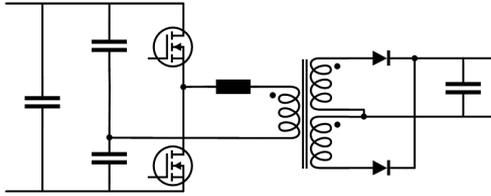
# New Active Output Clamping (for $V_{DDO} < UVLO$ )

- > Motivation:
  - > During startup, while  $V_{dd\_highside} < UVLO$ , high  $dV_{DS}/dt$  can cause  $V_G$  to be lifted above  $V_{th}$
  - > This can cause erratic turn on, thus shoot-through
- > Wanted:
  - > Fast clamping of the output
  - > Active already at lowest possible driver-supply voltage  $V_{DDA}$  resp.  $V_{DDB}$



# New Active Output Clamping (for $V_{DDO} < UVLO$ )

## Benefit in the end-application



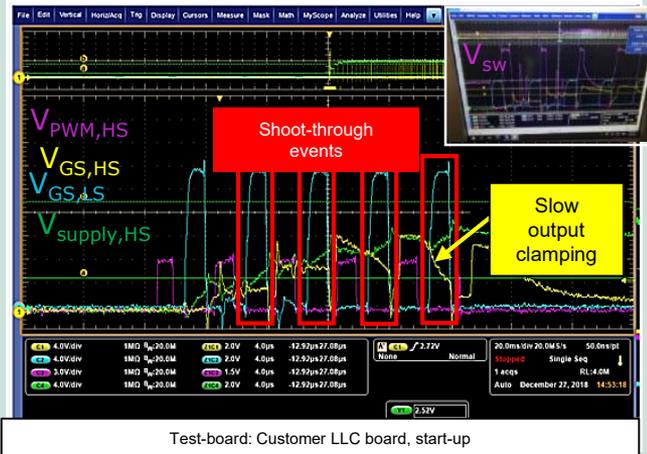
### Critical topology/condition

- › LLC with split resonant cap
- › Bootstrap circuit used
- › Any condition when bootstrap supply is below UVLO (start-up, burst mode)



### Slow RC output clamping

(old 2EDi marking A, some competitors products)

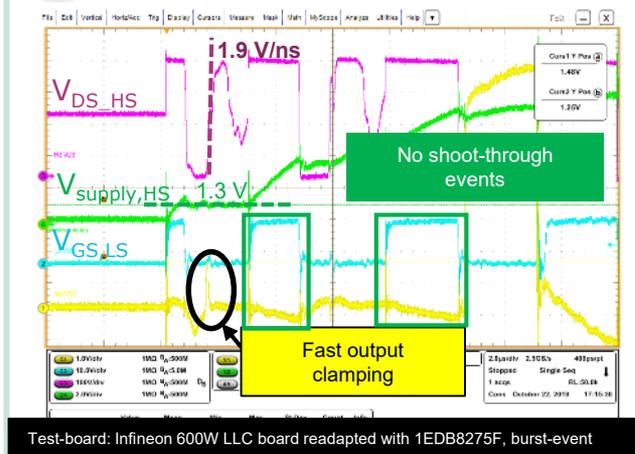


**Shoot-through** due to driver slow output clamping for boot supply below UVLO



### Fast active output clamping

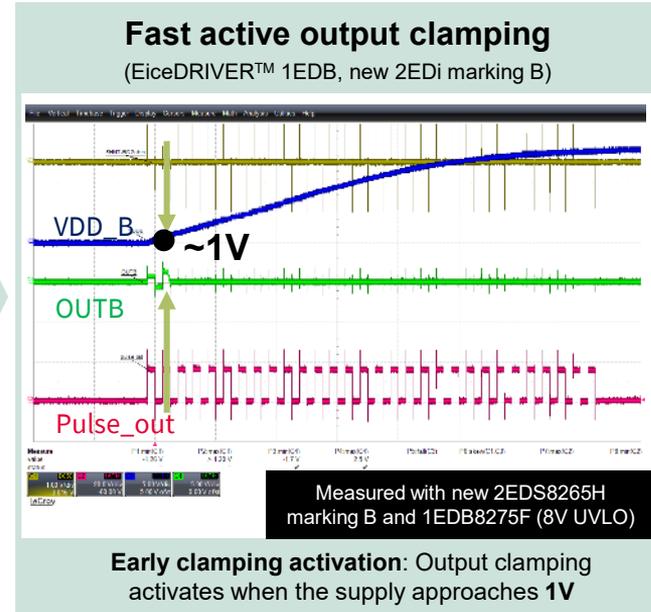
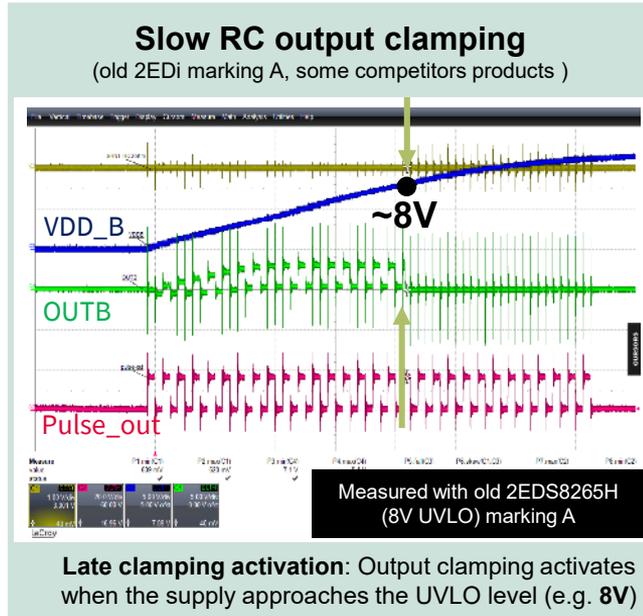
(EiceDRIVER™ 1EDB, new 2EDi marking B)



**No shoot-through** thanks to driver fast output clamping for boot supply below UVLO

# New Active Output Clamping (for VDDO < UVLO)

## In action...



- › Results from component verification measurements; pulse (Pulse\_out) forced on the Gate Driver output (OUT) and supply (VDD\_B) raised with controlled ramp; due to selected switching frequency, slow clamping mechanisms are not visible

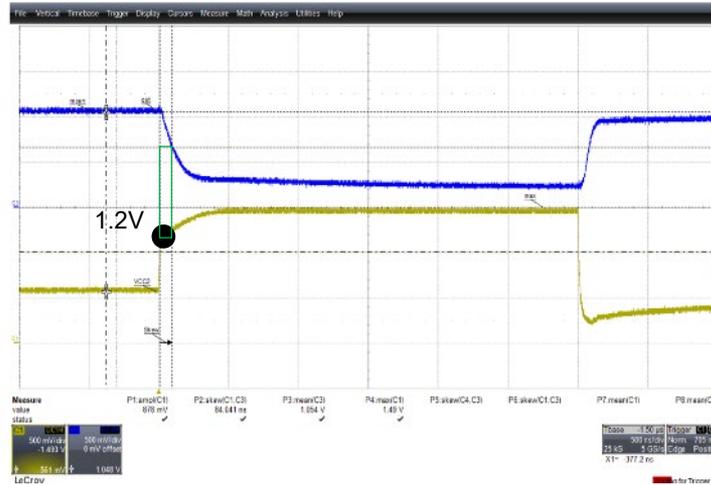
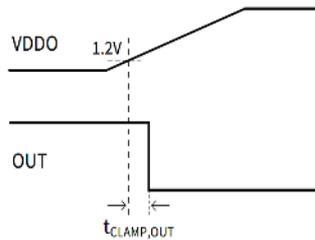
# New Active Output Clamping (for VDDO < UVLO)

## 1EDB clamping activation time

Activation time of output clamping in UVLO condition <sup>3)</sup>	$t_{CLAMP,OUT}$	-	20	-	ns	see <a href="#">Figure 10</a>
--	-----------------	---	----	---	----	-------------------------------



3) parameter not subject to production test - verified by design / characterization



- > Parameter measured raising the 1EDB output supply (fast ramp) and forcing 1V on the output.
- > The activation time is the time needed from the driver to start clamping the output after the supply has reached the trigger value (~1V)

## Key take-aways

---

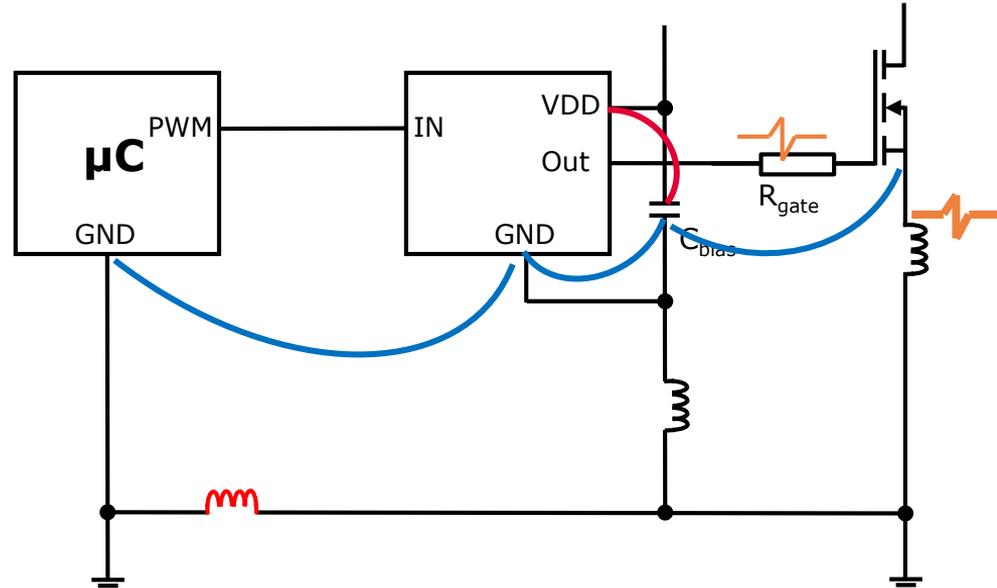
- › If you compare datasheets or look for a suitable driver:
  - Don't be fooled by the cover-page parameters
  - Compare currents wrt. to their load type and voltage spec.
  - Compare timings wrt. their spec-conditions
  - Focus on special application requirements like
    - UVLO level, precision, timing, speed for ON and OFF
    - Timing precision of the driver

# Layout considerations



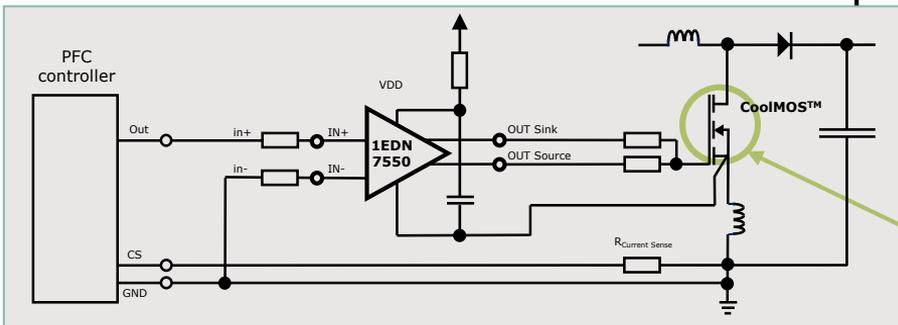
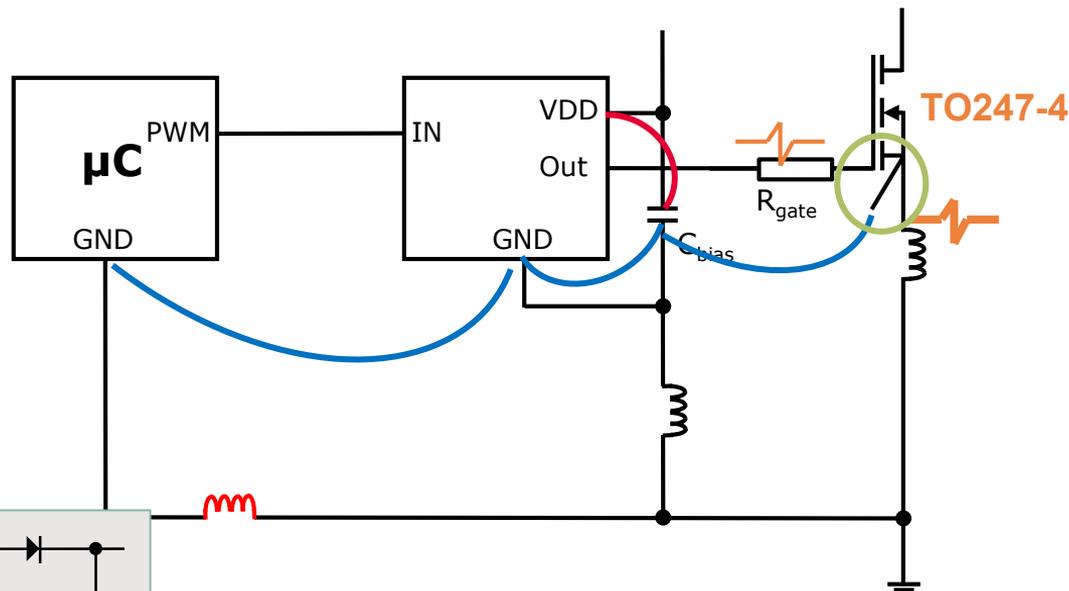
# Layout considerations

- > Keep Signal-GND away from Power-GND
- > Use short, thick traces
- > Use local, 5x wider traces underneath the signal as return
- > Do not span areas, they're nice antennas



# Layout considerations

- > Keep Signal-GND away from Power-GND
- > Use short, thick traces
- > Use local, 5x wider traces underneath the signal as return
- > Do not span areas, they're nice antennas

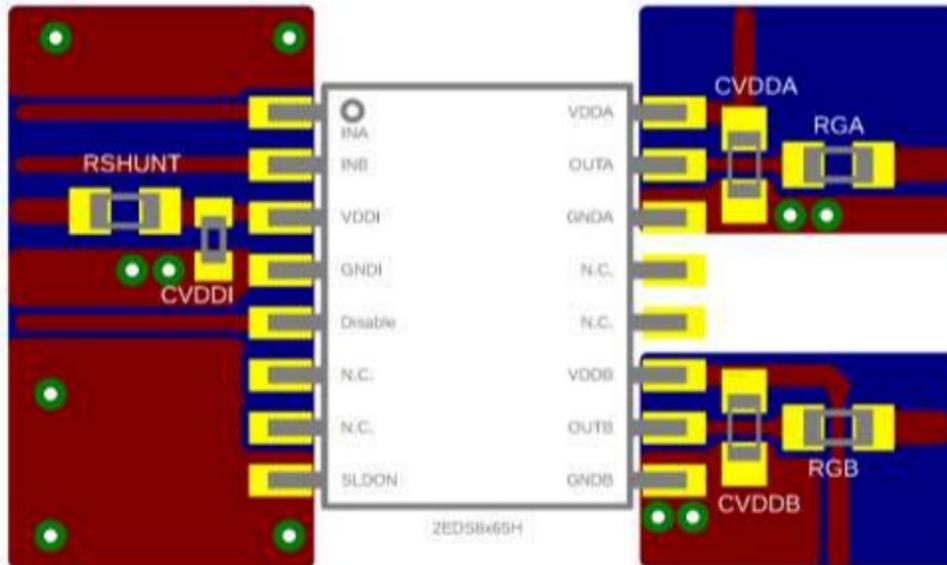
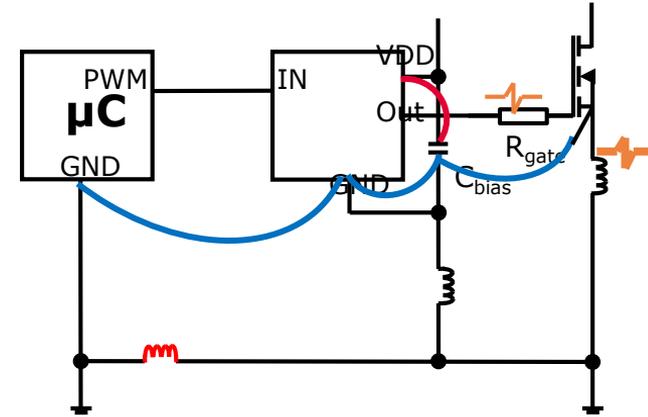


> GND connection on 4pin device

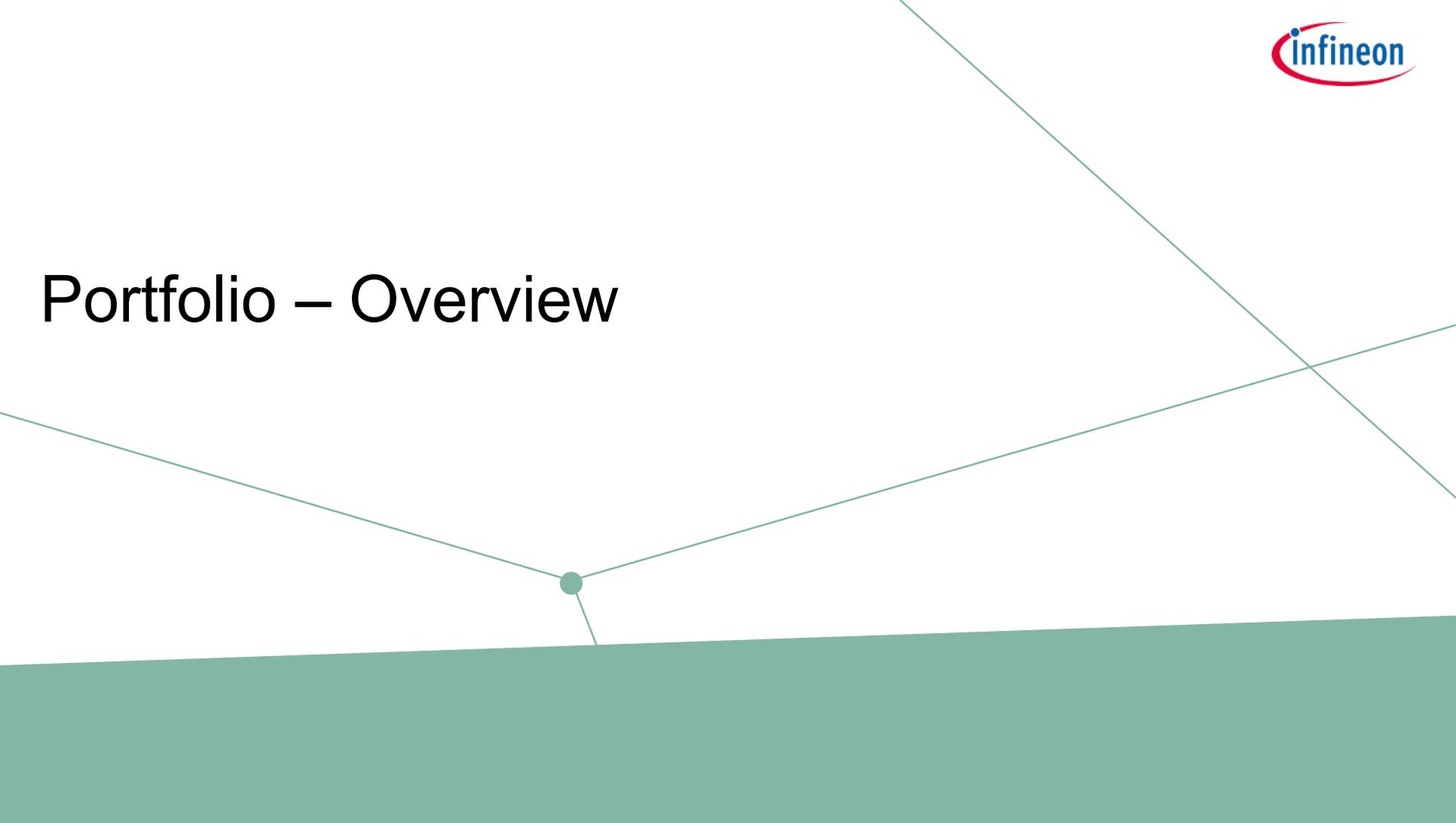


# Layout considerations

- > Keep Signal-GND away from Power-GND
- > Use short, thick traces with low impedance return
- > Use local, 5x wider traces underneath the signal as return



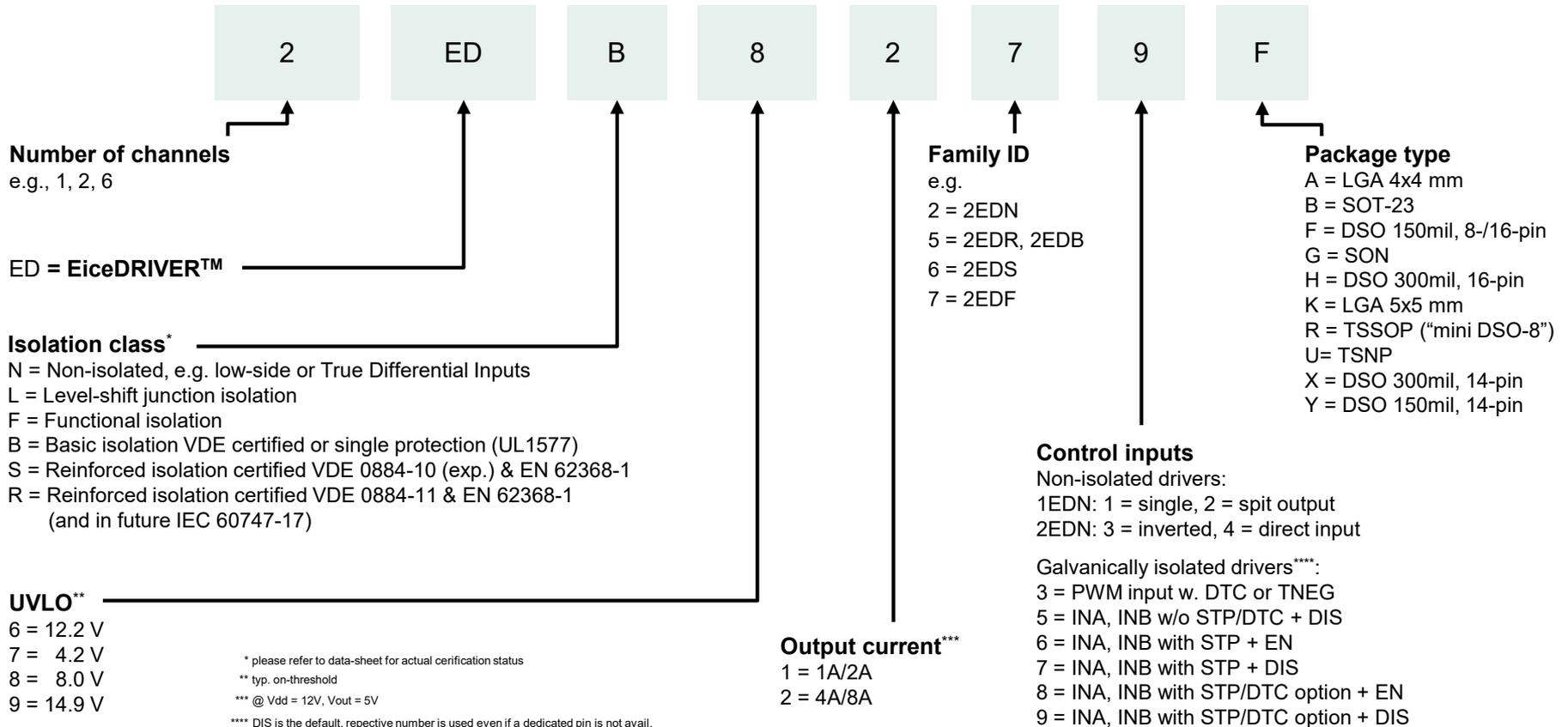
# Portfolio – Overview





# Gate Driver IC Nomenclature of PSS Division

## - Guideline -



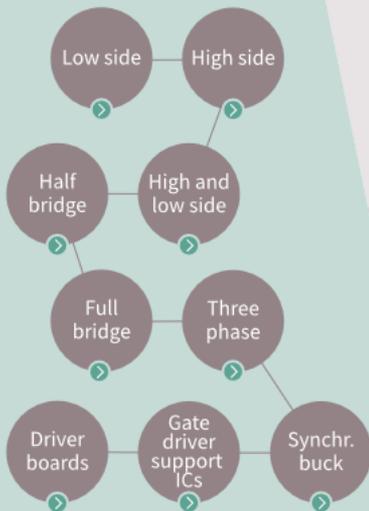
# Navigating the Infineon Gate-Driver IC world

Visit [www.infineon.com/gatedriver](http://www.infineon.com/gatedriver)



## EiceDRIVER™ Gate Driver Selection

### By configuration

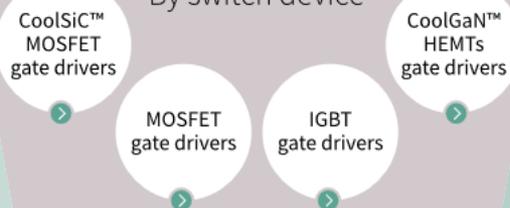


> Gate driver forum

### By isolation



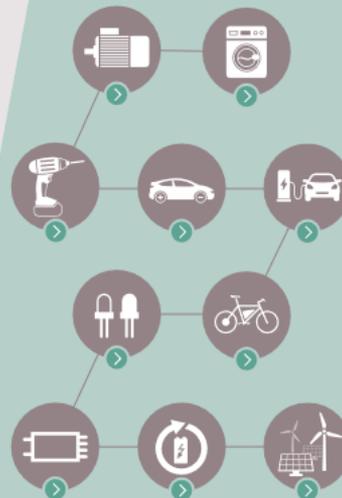
### By switch device



> Gate driver selection guide

> Gate driver finder

### By application



> Automotive qualified



Every Switch needs a Driver



# "Common DNA" through-out the portfolio for High System Efficiency and Robust & Save Operation



		Low-side		Non-isolated	Isolated			
		1-channel	2-channel	1-channel	1-channel	2-channel		
Product examples		1EDN7511B	2EDN7524R	1EDN7550B	1EDB7275F	2EDF7275F		
Low resistance rail-to-rail output stages	source	0.85 Ω / 4 A	0.7 Ω / 4 A	0.85 Ω / 4A	0.95 Ω / 4 A	0.85 Ω / 4 A	Minimizes MOSFET switching losses	High System Efficiency
	sink	0.35 Ω / 8 A	0.55 Ω / 4 A	0.35 Ω / 8 A	0.48 Ω / 8 A	0.35 Ω / 8 A		
Input-to-output propagation delay accuracy	on	+ 6 ns	+ 4 ns	+ 10 ns	+ 4 ns	+ 7 ns	Minimizes dead-time losses	
	off	- 4 ns	- 4 ns	- 7 ns	- 4 ns	- 6 ns		
Input robustness	abs. max.	- 10V	- 10V	+/- 150V (TDI)	- 5V	- 5V	Noise margin	Robust and Save System Operation
Fast output clamping			20 ns	20 ns	20 ns	20 ns	Avoids half-bridge shoot-through during boot-strapped start-up	
UVLO options	typ. off threshold	3.9 V	3.9 V	3.9 V	3.9 V	3.9 V	Reduces risk of thermal overstress of power switch, if auxiliary supply drops	
		7.0 V	7.0 V	7.0 V	7.0 V	7.0 V		
				14.4 V	11.5 V, 14.4 V	12.9 V, 14.4 V		
Reverse current robustness	abs. max.	5 A <sub>peak</sub>	5 A <sub>peak</sub>	5 A <sub>peak</sub>	5 A <sub>peak</sub>	5 A <sub>peak</sub>	No need for Schottky diodes to protect gate-driver output	
Galvanic isolation		n.a.			UL 1577, VDE 0884		Rugged ground-loop separation	
CMR / CMTI		Truly Differential Inputs			> 300 V/ns	> 150 V/ns	Immune against switching noise	

# Low-Side Gate-Driver ICs

## Portfolio and Roadmap

(Q2CY21; PL21B)

1-ch

1EDN Family	
	4 A / 8 A SOT23-5 SOT23-6 WSON-6
	1EDN7512B 1EDN7511B 1EDN8511B 1EDN7512G

2-ch

2EDN Family	
	4 A / 4 A or 5 A / 5 A DSO-8 TSSOP-8 WSON-8
	2EDN752xF 2EDN852xF 2EDN752xR 2EDN852xR 2EDN752xG 2EDN7424x

In Production

### 2EDN Expansion1

- New:** 20 ns fast output clamp
- New:** 2  $\mu$ s UVLO start-up time
- New:** SOT23-6
- New:** TSNP-6



now\*

May-21\*

\*DSO, TSSOP, SOT

2021

### 1EDN Exp\_1

**New:** 12 A<sub>src</sub> / 25 A<sub>sink</sub> (VDD up to 12 V)



Source-down OptiMOS in IBC & HSC with switched capacitor topologies

Center-tapped SR in Telco DCDC-Bricks & High-power SMPS

2022

# Truly Differential Input Gate-Driver ICs Portfolio and Roadmap

1-ch

## 1EDN-TDI Family

Truly Differential Inputs

4 A / 8 A

SOT23-6

TSNP-6



1EDN7550B  
1EDN8550B  
1EDN7550U

In Production

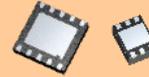
## 1EDN71x6 Family for 100 V GaN

TDI for 150 V CMR

DT selectable

Negative charge pump option

3x3 mm SON-10, 1.8x1.8 mm TSNP-7



Feb-21

Apr-21

2021

## 1EDN-TDI Exp\_1

**New:** Eliminates external  $R_{CM}$

SOT23-6: up to +/-150 V

TSNP-6: +/- 120 V



FB-SR in Telco DCDC Bricks  
IBC & HSC in switched capacitor  
topologies

Boost-PFC w. KelvinSource MOSFET  
Totem-pole PFC  
FB-Sync Rec  
HB in Battery powered motor drives  
PV optimizer

2022

# Junction Isolated Gate-Driver ICs

## Portfolio and Roadmap



(Q2CY21; PL88I)

2-ch

### 2EDL8x2x Family

120 V int. boot-strap diode  
2 A to 4 A  
TDI option  
SON-8 4x4



2EDL802xG  
2EDL812xG  
2EDL8012G  
2EDL8112G

### Wireless Charging Driver

60 V int. boot-strap diode  
2 A  
SON-10 4x4



WDCSC0006

### 2EDL8x2x Exp1



**NEW:** SON-10 3x3 (telco DCDC)

May-21

Nov-21

### HB 120 V GaN driver

120 V int. boot-strap diode  
Active Miller Clamp  
TSNP-12 2x2



Aug-21

Q2-22

### HB 120 V telco DCDC Driver

120 V internal boot-strap diode  
SON-8 4x4  
SON-10 3x3  
DSO-8 (solar and SR)



Jan-22

Oct-22

### 6EDL7141

70 V 3-phase Smart **Motor Driver**  
VQFN-48 7x7



Oct-20

May-21

6-ch

In Production

2021

2022

# Galvanically Isolated Gate-Driver ICs

## Portfolio and Roadmap



(Q2CY21; PL21B & PL88I)

1-ch



**1EDi-GaN**

DSO-16 300mil  
DSO-16 150mil  
LGA-13 5x5

1EDS5663H  
1EDF5673F  
1EDF5673K

**1EDB-Family**

+5.6 A source / -10.2 A sink  
20 ns fast output clamp  
5  $\mu$ s UVLO start-up time  
4 V to 15 V UVLO options  
300 V/ns CMTI  
 $V_{ISO} = 3 \text{ kV}_{rms}$  (UL1577)  
150 mil DSO-8

1EDB6275F  
1EDB7275F  
1EDB8275F  
1EDB9275F



2-ch



**2EDi Family**

1 A / 2 A, 4 A / 8 A  
DSO-16 300mil  
DSO-16 150mil  
LGA-13 5x5

2EDS9265H  
2EDS8265H  
2EDS8165H  
2EDF9275F  
2EDF7275F  
2EDF7175F  
2EDF7275K  
2EDF7235K

**2EDi Expansion1**

**New:** STP, DTC (option)  
**New:** 20 ns fast output clamp  
**New:** 2  $\mu$ s UVLO start-up time  
**New:** 300 V/ns CMTI  
**New:** VDE 0884-11  
**New:** DSO-14 300mil  
**New:** DSO-14 150mil  
**New:** LGA-13 4x4



May-21
Oct.-21

In Production

2021

2022

# 2-channel isolated gate-driver IC Portfolio and Roadmap in detail

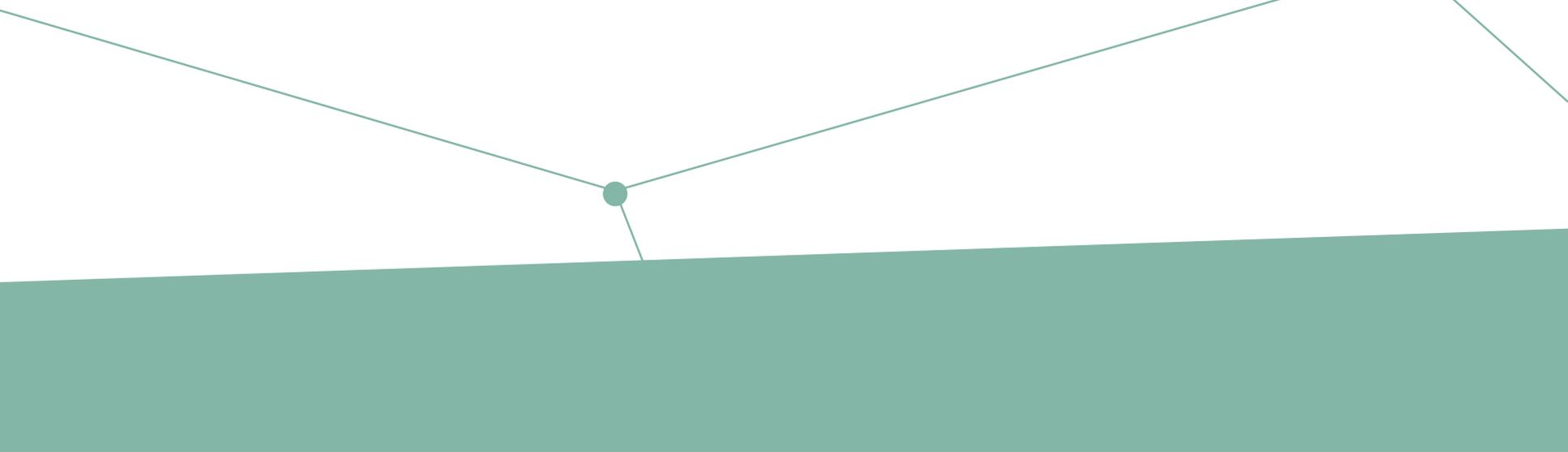
Product	Package		Isolation Certification	Outputs stage		Controls		
	Type	Pins		source/sink	UVLO	inputs	STP/DTC option	DIS/EN
2EDS8165H	300mil DSO	16 pin	$V_{IOTM} = 8kV_{pk}$ VDE-10	1A / 2A	8V	INA, INB	no	DIS
2EDS8265H	300mil DSO	16 pin	$V_{IOTM} = 8kV_{pk}$ VDE-10	4A / 8A	8V	INA, INB	no	DIS
2EDS9265H	300mil DSO	16 pin	$V_{IOTM} = 8kV_{pk}$ VDE-10	4A / 8A	13V	INA, INB	no	DIS
2EDR8259H	300mil DSO	16 pin	$V_{IOTM} = 8kV_{pk}$ <b>VDE-11</b>	4A / 8A	8V	INA, INB	<b>yes</b>	DIS
2EDR7259X	300mil DSO	<b>14 pin</b>	$V_{IOTM} = 8kV_{pk}$ <b>VDE-11</b>	4A / 8A	4V	INA, INB	<b>yes</b>	DIS
2EDR8259X	300mil DSO	<b>14 pin</b>	$V_{IOTM} = 8kV_{pk}$ <b>VDE-11</b>	4A / 8A	8V	INA, INB	<b>yes</b>	DIS
2EDR9259X	300mil DSO	<b>14 pin</b>	$V_{IOTM} = 8kV_{pk}$ <b>VDE-11</b>	4A / 8A	<b>15V</b>	INA, INB	<b>yes</b>	DIS
2EDF6258X	300mil DSO	<b>14 pin</b>	<b>functional</b>	4A / 8A	<b>12V</b>	INA, INB	<b>yes</b>	<b>EN</b>
2EDF7175F	150mil DSO	16 pin	1.5kV <sub>DC</sub> functional	1A / 2A	4V	INA, INB	no	DIS
2EDF7275F	150mil DSO	16 pin	1.5kV <sub>DC</sub> functional	4A / 8A	4V	INA, INB	no	DIS
2EDF9275F	150mil DSO	16 pin	1.5kV <sub>DC</sub> functional	4A / 8A	13V	INA, INB	no	DIS
2EDB8259F	150mil DSO	16 pin	$V_{ISO} = 3kV_{rms}$ <b>UL1577</b>	4A / 8A	8V	INA, INB	<b>yes</b>	DIS
2EDB7259Y	150mil DSO	<b>14 pin</b>	$V_{ISO} = 3kV_{rms}$ <b>UL1577</b>	4A / 8A	4V	INA, INB	<b>yes</b>	DIS
2EDB8259Y	150mil DSO	<b>14 pin</b>	$V_{ISO} = 3kV_{rms}$ <b>UL1577</b>	4A / 8A	<b>8V</b>	INA, INB	<b>yes</b>	DIS
2EDB9259Y	150mil DSO	<b>14 pin</b>	$V_{ISO} = 3kV_{rms}$ <b>UL1577</b>	4A / 8A	<b>15V</b>	INA, INB	<b>yes</b>	DIS
2EDF7275K	5x5 LGA	13-pin	1.5kV <sub>DC</sub> functional	4A / 8A	4V	INA, INB	no	DIS
2EDF7235K	5x5 LGA	13-pin	1.5kV <sub>DC</sub> functional	4A / 8A	4V	INA, INB	DTC	DIS
2EDB7259K	5x5 LGA	13-pin	$V_{ISO} = 2.5kV_{rms}$ <b>UL1577</b>	4A / 8A	4V	INA, INB	<b>yes</b>	DIS
2EDB8259K	5x5 LGA	13-pin	$V_{ISO} = 2.5kV_{rms}$ <b>UL1577</b>	4A / 8A	<b>8V</b>	INA, INB	<b>yes</b>	DIS
2EDB7259A	<b>4x4 LGA</b>	13-pin	$V_{ISO} = 2.25kV_{rms}$ <b>UL1577</b>	4A / 8A	4V	INA, INB	<b>yes</b>	DIS
2EDB8259A	<b>4x4 LGA</b>	13-pin	$V_{ISO} = 2.25kV_{rms}$ <b>UL1577</b>	4A / 8A	<b>8V</b>	INA, INB	<b>yes</b>	DIS

Note: VDE 0884-10 expired, but IEC 62368-1 survives



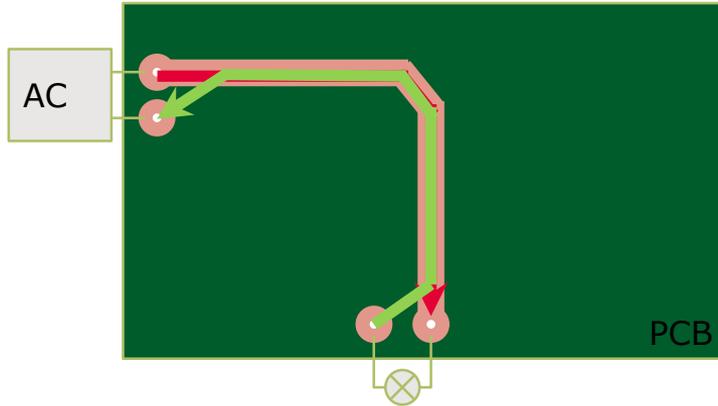
Part of your life. Part of tomorrow.

# Addendum - layout



# Exkurs – Layout – the way AC flows

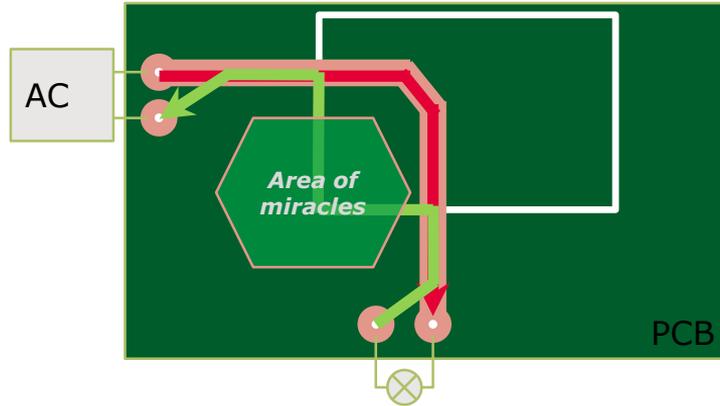
- › Complete GND plane assumed



- › AC return current
  - uses the low impedance trace
  - not the low ohmic trace

# Layout – the way AC flows

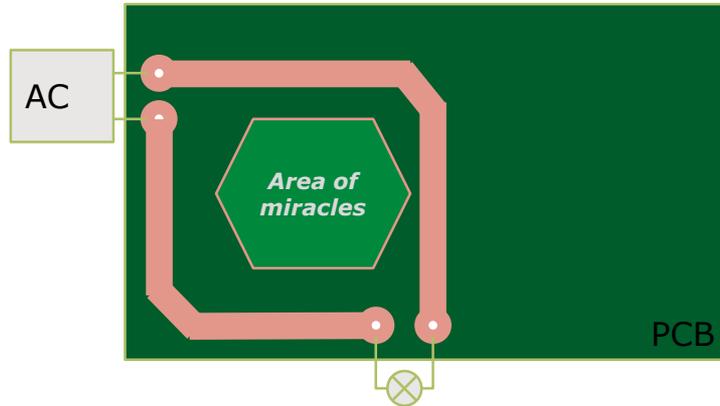
- › Fractured GND plane assumed



- › AC return current
  - uses an unknown way
  - induces *wonderful* signals into parts not intended to be meant

## Layout – the way AC flows

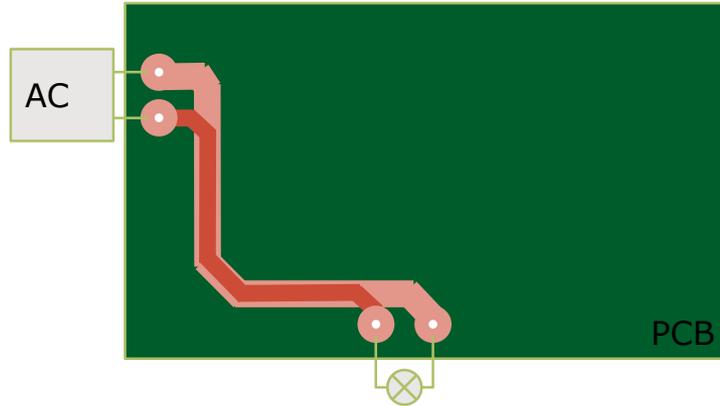
- › Fractured or complete GND plane assumed



- › AC return current
  - forced in a known path, but
  - spans a huge antenna area, generating radiated noise

## Layout – the way AC flows

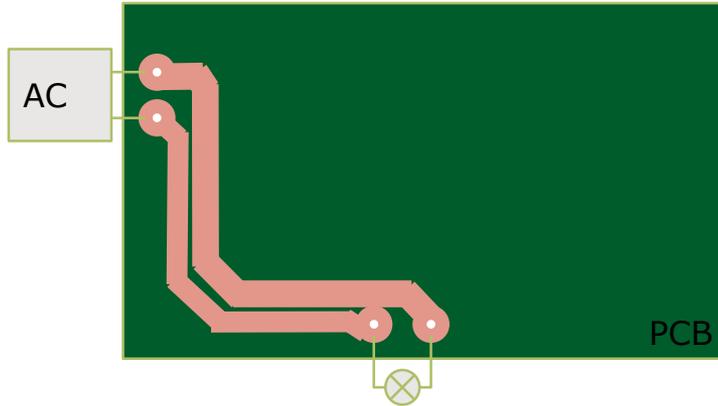
- › Fractured or complete GND plane assumed



- › AC return current
  - forced in a low impedance, non-disturbing path

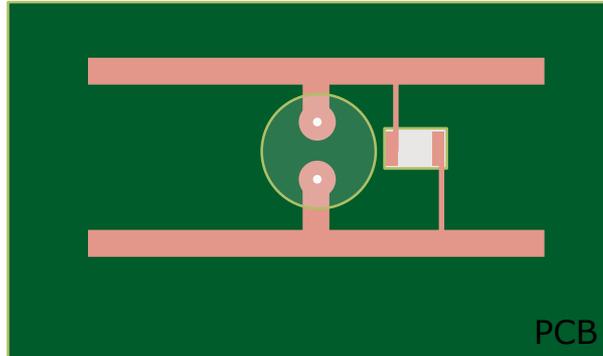
## Layout – the way AC flows

- › Fractured or complete GND plane assumed



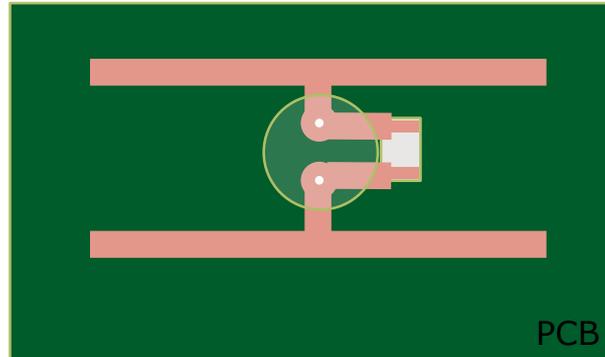
- › AC return current – alternative on single side PCB
  - forced in a low impedance, non-disturbing path

## Exkurs2 – Layout – blocking caps - Example



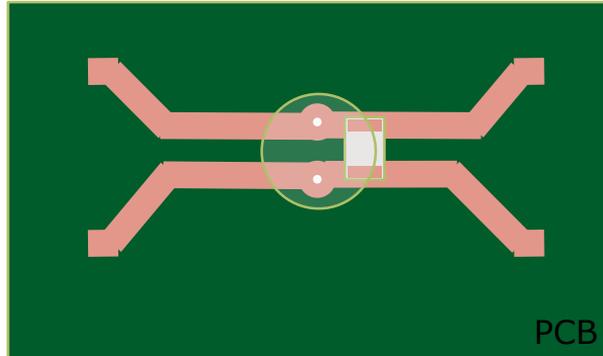
- › Absolutely horrible ...
  - C13 (100nF) is de-facto *not connected* due to trace impedance

## Exkurs2 – Layout – blocking caps - Example



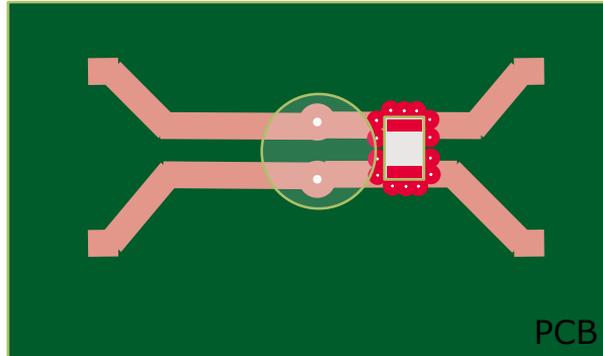
- › Nearly absolutely horrible ...
  - C13 (100nF) is de-facto *not connected* due to trace impedance

## Exkurs2 – Layout – blocking caps - Example



- › I'd prefer this way!
  - Current forced to use both caps
  - Small spanned area
  - Low impedance traces

## Exkurs2 – Layout – blocking caps - Example



- › I'd prefer this way, if you really need the other pcb-side!
  - Please, place the cap onto the trace, avoid contacts
  - If you really need contacts, use lots of them